# A Complete Bibliography of Publications in *Technometrics* for the decade 1970–1979

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## Title word cross-reference

0.5 [Lad77]. 18 [Joh73a]. 2 [BN72]. $2^m$ [SC71]. $2^n$ [Joh79]. $2^{n-k}$ [Joh79]. $2 \times 2$ [MDM77]. 3 [Lin79]. $3^n$ [Hok74]. $^4$ [Dic74]. $^5$ [Dic74]. $^n$ [TW70]. $A$ [Bad70, Bor72]. $\alpha$ [AS73, McC78a]. $A \subset B$ [Bad70, Bor72]. $B$ [Bad70, Bor72]. $\beta$ [AS73, GPU76]. $C_P$ [Mal73, Ano73i, Ken71]. $D$ [GK77a, JD75, Luc78, Mit74a, Mit74b, MB78a, MB78b, NGM70]. $F$ [DW72, DW73, HH77, J.79u, Joh73b, Obe77, Pap72, PW72, HB71]. $k$ [HP73, Ode71, WK71, Zei73]. $\log Y$ [Scl72]. $m$ [FM77, HP73]. $m \leq 6$ [SC71]. $N$ [Shu71, Gre70b, Sap73]. $n = 92$ [Wat70a]. $O$ [MHL74]. $p$ [Dun78a, FM77, For72, Lad77, MC72]. $P(Y < X)$ [KKS76]. $P[Y < X]$ [WK77]. $\Pr(Y < X)$ [Dow73]. $\Pr\{Y < X\}$ [JTS75, Ton74, Ton75]. $R^2$ [DH74]. $s$ [Bha73, Lik74]. $s^n$ [AT79]. $\sigma^2$ [JMM78]. $t$ [AS73, KP79, Ros75c, SI70, TC72, YM74]. $T^2$ [BJN71]. $T_M^2$ [JH79]. $V$ [SC71]. $W$ [GH79, HH73, HL76, Ste78, Tho75]. $X$ [Scl72]. $Y$ [Scl72]. $|X'X|$ [Ano71a, Ano72e, Ano73h, BD71, Dyk71, Eva79].

**-** [J.79u]. **-acceptability** [McC78a]. **-Blue** [MHL74]. **-Charts** [Dun78a]. **-content** [GPU76]. **-distribution** [TC72]. **-Distributions** [HB71]. **-Optimal** [Luc78, MB78b, Mit74a, Mit74b, MB78a]. **-Optimality** [JD75, NGM70]. **-optimum** [GK77a]. **-Sample** [Ode71]. **-sided** [BN72]. **-Solution** [Ros75c]. **-spare** [Bha73]. **-Spline** [Lin79]. **-Statistic** [DW72, HH77, PW72]. **-Statistics** [Pap72]. **-Test** [AS73, SI70]. **-Tests** [DW73, Obe77]. **-Transform** [HL76].

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**2** [Che71, J.79f, Sne74]. **21** [Kit81]. **25** [K.73a].

**3** [BCK78, J.76h].

**4** [J.77k].

**5** [J.78o].

**77** [Hea78]. **'78** [J.79n]. **781** [BS79].

**80f** [Kit81].

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**Bernard** [Gle77, Hel71b]. **Bernoulli** [Sap73]. **Bert** [K.71a]. **Bertram**
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[AF76, Her70, Sar71]. **Boundary** [And75]. **Bounds** [Fin76, FW74, Gru71b, Gru71c, JL79, KARR75, Law75a, Man70a, MF73, MG74, MF75a, MF77, Ury72]. **Bowker** [Web73]. **Box** [Add79, And70, Hil74, Kle77, GK77a, J.79p]. **Boyce** [Gor76]. **Bradley** [Bel70]. **Bradu** [Ano78e]. **Branch** [AF76]. **Branch-and-Bound** [AF76]. **Brandt** [Dav77]. **Bremner** [Kal75]. **Breslow** [J.79h]. **Bressler** [Kno71]. **Brian** [J.79i, K.71a, Ket75]. **Bridge** [ZNL79]. **Brillinger** [Weg76]. **Brodeau** [J.78m]. **Bronchitis** [Ens78]. **Bross** [Bon77]. **Brown** [K.71a, Hea78, Joh75]. **Brownian** [CF76, Nád73, PK76, SS74, Ser73]. **Bruce** [Rog70b]. **Brumat** [J.78i]. **Brunk** [Hal77b, Kal75]. **Brunner** [Jac80]. **Bryant** [J.76e, Hay73, J.76d]. **Buddy** [Rus73]. **Building** [Goo71]. **Bulk** [BR75]. **Burdick** [J.78j]. **Burman** [Wat70a]. **Burr** [Aus73]. **Business** [Ham75, J.78p, Joh75, Jon73, Kin79b, Hun70].

**C** [Bak74, Ban73, Boa79a, Cru78b, Dil71, Dun77a, For73, Gen77, Gil74, Gle78, GH75, Hay73, Hei79, Hil74, J.77b, J.77f, J.77e, J.77n, J.77m, J.77q, J.77p, J.78i, J.79d, Joh75, K.71e, K.73a, Kup71, Lyn78, Pre77, Sax72, Sen75, Sne72a, Ton72, Woo75, Woo74a]. **Calculation** [MT72, WB75]. **Calculations** [NL75]. **Calibration** [Kal71, MK70, MW75b, Nas78, Pep73, Shu72]. **Calus** [Boa79a]. **Cam** [Fre73b]. **Candidates** [Ano71f]. **Cardiac** [BKRS78]. **Care** [Gut73a, GDF78]. **Carl** [Gro77]. **Carlo** [Rel70]. **Case** [BR73, Dow73, Her70, KKS76, LO79, OL77, Sor73, Ton74, Ton75, WK77, JTS75]. **Categorical** [Dra79, Fed77]. **Category** [Ala71]. **Cauchy** [CC71]. **Causes** [Moe74]. **Cecily** [Ens78]. **Censored** [Ano73k, Bai72, Bai73, BAB72, Coh65, Coh75, Coh76, CN77, Dan70, DM78, EB73, EB79, Hoo79, KB75, Lem75, MN77, MS79, MHL74, NH72, Nel72b, Nel73, NH73, NK76, NM78, NS79, Pat76a, SH79, Sin71, TW72b, Zel72, BD73]. **Censoring** [Man71b]. **Centering** [Bro77]. **Central** [HP78, KP79]. **Centrosymmetric** [And73, Goo70]. **Certain** [BK70b, Dav79a, FB75, GH70, Gri73, Sch76]. **Chain** [Bri74, JK74]. **Chains** [WB71, Cra74, Doo72, Sys76]. **Change** [SS75]. **Changes** [Dic74]. **Character** [Dol70]. **Characteristic** [SLK79]. **Characteristics** [KKM79, Koy79, SR75]. **Characterization** [Ham72b, WRLI75, Sen75]. **Charges** [CH74]. **Charles** [Car74, Ens78, Gil74]. **Chart** [Aus73]. **Charts** [Chi75, Dun78a, GW71, J.76g, Rey75, RH78, SWD70, SWD74]. **Chatfield** [Dal77, J.79s, Pre77]. **Chatterjee** [Hah79]. **Checking** [Fra77]. **Chemical** [BA70, Sch75, SLM74, TB75]. **Chemistry** [FH79, LSYF79]. **Chi** [Dye73, SR75]. **Chi-Square** [SR75]. **Chinn** [Mil72a]. **Chistyakov** [Spr79]. **Choice** [Ait74, Ano77h, Bli72, GZ79, J.76g, Mac76, MK70, YC71]. **Choosing** [BS72, GHW79, NV73a]. **Chow** [Sim73]. **Chris** [Zac74]. **Christopher** [Dal77, J.79s]. **Chronic** [Ens78]. **Citation** [J.77d, J.77o]. **Civil** [K.73e, Kup71]. **Claim** [Hah77]. **Clark** [Hei76]. **Clarke** [Rog70b]. **Class** [AvdL70, BLB73, Bur73, GPS73, HSL76, SP77, Sha78, Tak72, TK72, VM79]. **Classical** [Obe77]. **Classification**

[CR79, Dun71, Ens76, HW75, Kus79, Low76, MA78]. **Classifications** [Goo71, HG73]. **Classified** [Dra79]. **Claudia** [Gro77]. **Clelland** [Joh75]. **Clinical** [FH79, LSYF79]. **Close** [MC72]. **Closed** [BM74, BM76, Ell76, PW77]. **Closed-Loop** [BM74, BM76, Ell76, PW77]. **Cloud** [DV78]. **Cloud-Seeding** [DV78]. **Cluster** [Ens76, Ket75]. **Clustering** [JK74]. **Clusters** [CBI79, YB76]. **Cochran** [J.78n, LH74]. **Code** [MBC79]. **Codes** [ZNL79]. **Coefficient** [Ano75e, Fil75, IM70, Kow71, Zei73, McC78a]. **Coefficients** [AR73, For72, JH73a, Wol77a]. **Coherence** [CP75]. **Collected** [K.73b]. **Collection** [J.76f]. **Combination** [Pap72]. **Combinations** [Coh72, Joh71a]. **Combining** [EP71, Lev70]. **Comment** [BC71, Cro71]. **commentaries** [CGO07]. **Comments** [Cor75, HK77, Mal73, DV79, MK70]. **Commission** [Car77b]. **Comparative** [BJN71, Bon76a]. **Comparing** [AB71, Ber78, Jae70, MDM77, Nel72a, Rub76, Sal75b, SS76, BN72]. **Comparison** [BM78, CM71, DW73, Dub73, Fed75, FH79, GK77a, GK77b, GH70, Gri70, Gru73b, GWM76, HN70, HW75, Hin77a, Kam73, Kam77, KP71, LSYF79, Low70, Luc76, MBC79, MH78, MPB70, MA78, San73, TA75, Ury76, Vin76, WC78, HK77]. **Comparisons** [IM70, SdV73, SU79, Ury76, BN72]. **Compartmental** [Gri79]. **Competing** [Moe74]. **Competitive** [Nay72]. **Complete** [Ano73k, Bis78, Coh65, Coh72, EB73, EB79, MF77, MHL74, SW72]. **Complex** [Bri74, Hun74, Sne76, Cas76]. **Component** [EP71, GC79, GH79, Gru71b, HL76, JM79, JS76, Krz79, Low76, MG74, Sar71, Var70, Bha73]. **Components** [CS76, DJ77a, GG70b, JH73a, JH79, MA78, Par78b, See70, SS78, TA71, Wol78, YC78]. **Composite** [HP78, Luc74]. **Composited** [Ede74]. **Compound** [BK70a, Cho79, Fal70, Boa73]. **Compressed** [Kam74]. **Comprised** [WK71]. **Computation** [Fur71, Sch76, Som70, Yue78, CGO07, K.71e]. **Computational** [Dav77, LH70]. **Computations** [J.77b, McC75a]. **Computer** [BH70, BCK61, Cha70a, Eva79, Gri72, Gro77, Hea78, Hub78, JB76, MBC79, Mil72b, Mit74b, Sie75, Wig76, BCK78, Mer72, Nay72]. **Computer-Aided** [Cha70a]. **Computers** [Cha70a, J.79q, Mul70]. **Computing** [HH73, KKM79, Mar76]. **Concentric** [CK79]. **Concept** [NGM70, Buc73]. **Concepts** [Bis72a, Car74, Sim76, SM76, Har77, Mih77, Mih75, Woo74a]. **concerning** [AK71, Law71]. **Condition** [Law77b, MH77]. **Conditional** [Ham72b, Jae74, Kap75, Sor71]. **Conditions** [Krz77, See73]. **Conference** [K.74e]. **Confidence** [AJ77, BS79, BWL78, Cha79, CM71, DV78, Dun78b, Eas78, EB78c, Fin76, FB75, Gaf78, Her70, Jae70, Jon71, Kam72, Kam73, Kam74, Kap75, Kus79, Lan72, Law78, LR78, Man70a, MF73, MG74, MF75a, MF77, MN77, Obe77, Pat76a, Ros75c, Sar71, Sch74a, SW75, Tar76, TBA70, TC75a, TC73, TS79, Ury72, TC72]. **Conflicting** [J.78b]. **Conjecture** [AK71]. **Conover** [Bha72]. **Consideration** [PDB77]. **Considerations** [GM79]. **Consistent** [IS76]. **Constant** [CK79, FR72]. **Constants** [Aus73]. **Constrained** [Ano76e, HB78, Sne75b, TW70]. **Constraints** [HS73].

**Constructed** [Dun78b]. **Constructing** [BCK61, BCK78]. **Construction** [CM71, EB78a, Law75a, Mit74a, Mit74b]. **Consultants** [Wat70b]. **contain** [HP73]. **content** [GPU76]. **Contigency** [MDM77]. **Contingency** [Gar71, Goo71, JK71, Odo78]. **Continuity** [Ham74]. **Continuous** [Che71, Fre74a, Hol75, RR76, Sac72, Sha79]. **Continuously** [Kao72]. **Contour** [GW71]. **Contrasts** [Par78b, Ury76]. **Contributions** [Ing78b, J.76a, J.78c]. **Control** [AB79, Ano77h, Aus73, BR79, BH78, Bin74b, Chi75, Dun78a, Dun77b, GW71, Gru73a, JM79, K.74a, Kab74, Luc73, Mac76, Pat73, RSO72, Rey75, ST73, SdV73, TW72a, BN72, Bis72b, J.79d, Kle77, Tsi78, Woo75, Ziz78]. **Convergence** [Ber72b, Sne70]. **Convolutions** [Bai74a]. **Cooley** [O'F73]. **Coordinate** [Kow70, Nád70a]. **Cornell** [Kup71]. **Correct** [Dun71]. **Correcting** [BH74]. **Correction** [AR79, Ham74, MM73]. **Correlated** [Shu71]. **Correlation** [Ano75e, AR73, BJ75, Fil75, Haw75, JB74, Kow71, Par70, Wol77a]. **Corrigenda** [Ano73f, Ano79e, Ano79f, Ano80a, Ano80b, Kit81, Mih77]. **Corrigendum** [Ano72g, Ano72e, Ano72f, Ano73g, Ano73h, Ano74f, Ano75e, Ano77a, Ano79g, Ano80c, Ano84]. **Cosines** [Cha70b]. **Cost** [Ano72g, Gue71b, RR76, Sch71b, ST73, TC75b, Ben76]. **Costs** [CH74, HS73, PS70]. **Countable** [Cra74]. **Counting** [CM71]. **Counts** [K.71d]. **Course** [Boa79a, Cro78, Geo72, Har70, Nas78, Sch74b, Str75]. **Covariance** [GC74, Ron77, Sne71, vN79]. **Covariances** [Cha70b]. **Covariate** [Har74]. **Covariates** [Kus79]. **Covariation** [J.76d, J.76e]. **Cox** [Ing75, J.79o, Cor75]. **Criteria** [Hoc72, J.78h, MPB70, Tho73]. **Criterion** [All71, Ano72e, Ano73h, Box70b, BD71, Bro79, Hel74, McL74a, ML75, NW79, SD77]. **Critical** [Zah75b]. **Cross** [Dra79, GHW79, J.79m, Mie74, Sim79, Wol78]. **Cross-Classified** [Dra79]. **Cross-Over** [Mie74]. **Cross-Tabulated** [Sim79]. **Cross-Validation** [GHW79]. **Cross-Validatory** [Wol78]. **Crossed** [HG73]. **Cryogenic** [Joi77]. **CSP** [Bla77]. **CSP-1** [Bla77]. **Cubic** [LW71]. **Cum** [Qua74b, Qua74a]. **Cumulative** [Bec74, Rey75]. **Current** [Dun78a]. **Curtailed** [Coh70, HM76a, SP72, SP74, SP77]. **Curve** [LS71b, Sne72b, SLM74]. **Curves** [SLK79, Dav70]. **CUSUM** [BJ75, JB74, MW75a, GW71]. **Cut** [BJ70b]. **Cutsem** [J.78m]. **Cyclic** [Ano74e]. **Cyrus** [Sid75].

**D** [Bon77, Bow77, Cas76, Dud79, Ens77, Fin75, Gib74, Gor76, Gou73, GH75, Hal77b, Har72, HK77, Ing75, J.75g, J.76h, J.77j, J.77k, J.78l, J.78k, J.78e, J.78d, J.78b, J.78o, J.79e, J.79o, J.79m, Joh73c, K.74c, Kal75, Law75b, Str75, Sys76, Wil70]. **Daniel** [Sne72a, Wei71, Lyn78]. **Data** [All74, Ano71a, BH70, Bli72, BHME73, BM76, Cha79, CR79, CG76, Dav77, Dyk71, Ell76, EB79, Ens76, Fed74b, Har75, HJ76, Hoo79, J.78f, J.78d, Jac80, JK71, KN74, KB75, Mal74, Man71a, MG74, Mar74, MN77, Mul70, Nea70, NH72, Nel72b, Nel73, NH73, O'F73, PW77, Pat76a, PS77, RTDM79, SH79, See73, Sne72b, Sne73, Ten72, WB74, Weg76, Wol74, Woo73, Zel72, BT74, Boa73, Dra79, Fed77,

Gen77, J.77m, J.79i, J.79c, Sim79, Sne72a, Wat73, Gen77, Lac71a]. **David** [Cra74, Doo72, For71, Kin79a, Mil72a, Ser73, Sim73, Weg76, Ano74e, Geo72, Gru71a, J.78c]. **Davis** [Ano80a]. **Dealing** [GS71, Gut73b]. **deCani** [Joh75]. **Decays** [SCSB76]. **Decision** [J.78h, Kin78, Kup71, Lac71b, Sym71, Win71, Hol73]. **Decisions** [J.78b, Ran70b]. **Decomposition** [Bod70, Fre74b, SCSB76]. **Defective** [BR73, SP74]. **DeFrancesco** [Sto76]. **DeGroot** [How77]. **Delay** [CP75]. **Deliveries** [BS72]. **Delphi** [J.76i]. **Densities** [BMP77, Par70]. **Density** [Gro71b, Spe71, Weg72, WRLI75]. **Departure** [Gre71]. **Depend** [Wio70]. **Dependent** [AvdL70, Bri74, Kus79, Moe74]. **Deposits** [CBI79]. **Depreciation** [CH74]. **Derivation** [Lad77]. **Derivative** [RJ78]. **Derivative-Free** [RJ78]. **Derivatives** [JB76, Wig76]. **Deriving** [Jon76a]. **Derman** [Sid75]. **Derrick** [K.74d]. **Design** [Add72, Ant77, Box70b, Box71, Buc73, Car74, Chi75, Con70, Cru78b, Dun78a, FM71, Gri73, HH74, Hil78, HS71, J.75a, J.76b, Joh78, Joi77, Luc76, Man72, Mar75, Mar76, MHC77, MH78, Mie74, OL77, PB77, SN77, See73, Ste75, Wat70a, Zac70, ZNL79, Joh73a, Kev75]. **Designing** [Joh71a, JC76, Tak72]. **Designs** [AT79, Ano72e, Ano73h, Ano73f, Ano76e, Ber72a, BD71, BD74, BH77, Cor75, DJ77a, Ede74, Eva79, GK77b, GG70b, HP78, HW75, Har79, HM72, Hok74, IR77, JD75, Joh79, Jon76a, Kle75, Luc74, Luc76, Luc78, Mit74a, Mit74b, MB78a, MB78b, MA78, OM72, Par78a, Roq76, See70, SM74, Sne75b, SM76, SC71, Ste72a, Tho73, TA75, Web71, GK77a, Ano74e, Cam77, Sne76]. **detect** [GDF78]. **Detecting** [CBI79, GW75, Gut73a, Shu71]. **Detection** [Ano79g, Coo77, Dav79b, Kit79, LE73, Ros75b, TM72, Kit81]. **Determination** [Ano72g, GW71, Gru73a, Gue71b, Hal77a, Jae74]. **Determines** [Nád71]. **Determining** [AB71, MW78]. **Development** [Kee75]. **Developments** [J.78i, J.78m, J.76b, J.79g, J.79f]. **Deviation** [BMH76]. **Deviations** [For72]. **Devices** [HN70]. **Diagnostic** [BG78, DM77]. **Difference** [Hah77]. **Differences** [Sal75b]. **Different** [Par70]. **Differential** [Bri73a, Cha75a, Fin75, JB76, Sac75, Str75, Wig76]. **Differentiation** [AB74]. **Diffusion** [Ser73]. **Digamma** [Lin79]. **Digital** [J.79q, Mih75, Mih77, Nel74]. **Dimension** [Cha79, vNS76, vN79]. **Dimensional** [GLV74]. **Dimensions** [DL70]. **Dimitri** [Ziz78]. **Direct** [Aro76, Goo71]. **Directional** [Wat73]. **Disciplines** [J.79v]. **Discounting** [RR76]. **Discrete** [AvdL70, Ano77h, Bai74a, DY70, Gri72, Mac76, Mih75, Mih77, PS77, Spr78, Odo77, Smi70a]. **Discretization** [Hol75]. **Discriminant** [Dun71, HH77, Krz77, Lac74b, Lac79, McC75a, McK76, McL72, McL74b, Sor73, vNS76, vN79]. **Discrimination** [AR79, BA70, DA73, DAH73, Har73a, Hil78, MPB70, Ng76]. **Discussion** [Ant77, Eas78, Ell76, FH79, Har73a, HM71, Hoo79, Law77b, LvNN73, Luc78, Mal74, Mar74, McD75, Par72, Sne75a, Wig76, Zel72]. **Disease** [Ens78]. **Disney** [Rog70b]. **Displays** [DM77, Tuk70]. **Distributed** [Bli72]. **Distribution** [AA74, Ang74, Ano72g, AJ77, Aus73, Bai72, BE73, Bai73, Bai74b, BB79,

BL71, Beh72, BMH76, BH73, CC71, CF76, CF77, Chi74, Coh65, CH73b, Coh73, Coh75, Coh76, CN77, CJ73, CL70, CL71, Dan70, DH74, DM78, Dun74, Dun78c, Dye73, EB73, EB74, Eng75, EB77a, EB77b, EB78a, EB78c, Fau70, FD70, GKS75, Gru71b, Gru71c, Gue71b, GS71, HBA71, Hah75, Ham72a, Har71, Has72, Haw72, Hel71a, Her70, HR75, Jos72, KN74, Kap75, KARR75, Law71, Law73, Law77a, Lem74, Lem75, LNN61, LC70, Lik74, Man72, MF73, Mat78, McD76, MW75a, MCL76, Nád70a, Nád71, O'B73, Par70, PK79, Pie73, RS71, RTDM79, RSO72, Riz71, SG71, Sar71, SA79, SLK79, SW72, SB72a, SW75, SU79, TBA70, Ury72, Wol77a, YM74, GPU76]. **distribution** [KP79, Smi76, TC72, Bel70]. **Distribution-Free** [HR75, MW75a, Ury72, Wol77a, Bel70]. **Distributional** [FP77]. **Distributions** [BL71, Beh70, Bry74, Bur73, CB75, Cha79, Che71, Cho79, DG72, Dub73, DA73, Eas78, Eva72, Fal70, GG70a, Gri70, Gro72, Hei76, HB71, Hol75, J.79u, KB75, KP71, Law75a, Law78, LF79, MF77, Nel75, NK76, NM78, NS79, Pat73, Pat76b, PS70, Rel70, Ron77, Sha78, Tak72, TW72b, WDFH73, Zac74, Fre74a, Smi70a, Che71, Fre74a]. **Divisibility** [Luk73]. **Dixon** [Hea78]. **Dodge** [KO77]. **Does** [Bad70, Bor72]. **Dolby** [Qua74b, Qua74a]. **Don** [Hac78]. **Donald** [Boa79a, Hay73, Leh71, Ran70c]. **Donna** [Boa79a]. **Dorfman** [GR72]. **Double** [ABA72, BE73, Bin74b, BR75, BH73, Eld74, Gue71a, Joh70a, Kap75, RS71, Ten72, Zac70]. **Double-Stage** [ABA72]. **Doubly** [HS71]. **Draper** [And70, GK77a]. **Drewes** [Leh71]. **Drift** [CF76, Nád73, PK76, SS74]. **Drogin** [Car77a]. **Dual** [MC73, ST73]. **Duckworth** [Wes71]. **Dud** [RJ78]. **Dudewicz** [Zie78]. **Dunkelberg** [Gle78]. **Duplicate** [TB75]. **Dynamic** [BM74, TW72a, Kev75, Sys75]. **Dynamic-Stochastic** [BM74].

**Each** [Gru71b, Joh70c, Joh70b, McL74b, Sar71]. **Earl** [Fin75, Str75]. **Early** [Ens78]. **Easy** [Gue77]. **Echo** [HT74]. **Econometric** [For71]. **Econometrica** [Fre73a, K.73c]. **Econometrics** [Fre73a, J.75h, Goo75, Goo76, Han73, Wil79a, J.77c]. **Economic** [BA70, Chi75, Dun78a, K.73c, Kao72, Mer72, Kee75]. **Economical** [Bli72, Gua71, Hok74]. **Economics** [Jon73]. **Économiques** [Gua71]. **Editor** [HK77, JTS75, And76, And77, Ano77g, BJ70a, BC79a, BM72, Fle71, Gar74, GMD+75, GH75, HOC+77, Ham70, Haw78, HJ73, JEBE74, Kru70, KBW72, Law76, LSP76, Lee79, MP72, Saw70, SBV79, Smi70b, Smi76, SM79, VK76, Wil79b, Wu73, ZA75]. **Educational** [Ger75]. **Edward** [Hay73, Woo74b, Zie78]. **Edwin** [J.77l]. **Effect** [BJ75, Bla77, CDR79, DR77, Dic74, JB74, RSO72, SG71, SOE75, TA71, Wic72]. **Effects** [HW75, Lac79, Nai74, Woo73, vNS76, vN79]. **Efficiencies** [BR73]. **Efficiency** [Igl73, LH70, MHL77a, MHL77b, PS70]. **Efficient** [BL74a, Her70, Jos72, KKS76, MF75b, MF77]. **Ehrenberg** [Gen77]. **Ehrenfeld** [Ano77a]. **Eigenanalysis** [Haw75]. **Eight** [Ens78]. **Eighteen** [Joh78]. **Einfuhrung** [Ens77]. **Elderton** [Dav70]. **Eleanor** [K.71a]. **Elementary** [Fin75, Hac78, Har77, J.76c, Mye74]. **Elements** [WK71].

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**F**
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**Finite** [Gro72, Ray70, WB71, Zac70, Ham75, Spr72]. **Finney** [Gou73]. **First**
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**G** [Add79, Bis72b, Boa79a, Ehr77, Eri72, Fie73, Gil74, GH75, Ham75, Har70, Har75, Hun74, J.76c, J.77l, J.78n, J.78e, J.78m, J.78j, Jon73, K.71d, K.74c, Kle77, Kno71, Lac74a, Man71c, MK70, McC72, Mil72a, Ram73, Ran70c, Sax72, Sch75, Sim79, Ton72, Tsi78, Wil79a]. **Gabriel** [Ano80a]. **Gambling** [Bon76b]. **Game** [Tan70]. **Gamma** [Ano73k, BG74, CN77, DG72, EB77b, EB78a, Gro71b, HBA71, Joh70b, O'B73, Ron77, SB72a, WK71, GH75, LF79]. **Gani** [J75e]. **Gap** [HD70]. **Gary** [Mar75]. **Gass** [Ran70a]. **Gaussian** [BB79, CF76, CF77, PK79, WY78]. **Gene** [CGO07]. **General** [AvdL70, AS73, Eva72, Hel74, SB72b, Tar76, TC75b, Bha73, GDF78]. **Generalization** [CJ73, HK75, ML75, Ell78]. **Generalizations** [Nel75]. **Generalized** [Aus73, BL71, GG70a, GHW79, HBA71, Hem75, HB78, Mar70, Sal75a, Ban73, Gow72, Urq73]. **Generated** [JB76, Wig76]. **Generating** [Ron77]. **Generation** [BJ70b, Jae74]. **Gentle** [Smi76]. **Geo** [Jon76b]. **Geo-Science** [Jon76b]. **Geomathematics** [Jon76b]. **Geometric** [AA74, RH78, Ste72b, Wic72]. **George** [And70, Fie73, Hil74, K.73d, Mih75, Mih77, Wil79a]. **Gerald** [Buc73, Dun77b, Web73]. **GERT** [KO77, Whi70]. **Gestion** [Gua71]. **Gibbons** [Dud79, Joh73c]. **Gibbs** [Bry71]. **Gibbs-Type** [Bry71]. **Gibson** [J.79m]. **Gipps** [GH75]. **Giri** [Hei79]. **Given** [Cha79, Hal77a]. **Glenn** [Ing78a]. **Gleser** [Sid75]. **Gnanadesikan** [Gri73, J.78f]. **Golub** [CGO07].

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**H** [Ano74e, Bow78, CGO07, Fed74a, Hal77b, Har72, HK77, How77, J.75g, J.76d, J.76e, J.76i, J.76h, J.78c, J.78b, J.79q, J.79k, J.79v, Jac80, JTS75, K.73b, K.73a, Kal75, Kin79b, Kra76, Lac74a, Law75b, Man73, Mer72, Ran70b, Ros75a, Sne74, Sne76, Ste75, Sto76, Sym71, Web73]. **H-Function** [J.79v]. **Haan** [Ber72b]. **Haber** [Qua71]. **Haitovsky** [Fre75]. **Haley** [J.79n]. **Half** [Zah75a, Zah75b]. **Half-Normal** [Zah75a, Zah75b]. **Hamburg** [Kin78, Win71]. **Hamdan** [Ano75f]. **Hampel** [Law75b]. **Handbook** [J.78g, K.71b, J.79j]. **Handling** [Gut73a, GDF78]. **Hannan** [Cle72a]. **Harald** [K.74b]. **Harold** [Dyk76, J.77g, J.79j, Sne76, Sta70]. **Harter** [Har72, J.75g, J.76h, Ano70f]. **Hartley** [Sne74]. **Having** [AR73, BL71]. **Hays** [Lac71b]. **Hazard** [Dan70, Jon71, Nád70b, Nel72b, Sha78]. **Hazurbazar** [Ing78b]. **Health** [J.79h]. **Heavy** [Bry74]. **Heavy-Tailed** [Bry74]. **Helge** [Boa79b]. **Helmuth** [Ens76]. **Hemker** [K.73a]. **Henri** [Fre74b, Han73]. **Henrick** [Sch74b]. **Henry** [Sal75a, Woo74b]. **Henschke** [Gro77]. **Herbert** [Gru71a, Sim73]. **Hess** [K.73a]. **Heteroscedasticity** [PB77, PDB77]. **Hickman** [Ram73]. **Hicks** [Car74]. **Higher** [Nai74]. **Higher-Way** [Nai74]. **Highway** [Ano73j, Mar73]. **Hilary** [Hun70]. **Hill** [J.78q, J.78q]. **Hilton** [Ram73]. **Hine** [Boa79a]. **Hinkley** [Ing75, J.79o]. **Hirsch** [J.79r]. **History** [Ens78, J.78k]. **Hoel** [Gil74, Jon73, Sax72, Ton72, Eri72]. **Hoerl** [Ano70f]. **Hogg** [Hei78]. **Holland** [Odo77]. **Hollander** [Gib74]. **Homogeneity** [Cho79, Sch71a]. **Honor** [J.75h, K.73d]. **Honour** [J.77l, K.74b]. **Hooper** [Fre73a]. **Hordijk** [Sys75]. **Hotelling** [JH79]. **Howard** [Hac78, Har70, Lut73]. **Huang** [For71]. **Huber** [Law75b]. **Human** [Bon77]. **Hunter** [Add79, Add79, Gra72]. **Hurst** [Dun77b]. **Hybrid** [Roq76]. **Hyperbinomial** [Gro72]. **Hyperbola** [WB74]. **Hypergeometric** [Hel71a, J.77g, J.79j]. **Hypotheses** [BH73]. **Hypothesis** [Leo70, McD75, Obe75, SLK79].

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**Inversion** [Fra77]. **Investigation** [GS71]. **Invited** [HM71]. **Involving** [And73, DW72, Har79, McK76, Riz71]. **Ionospheric** [HM73]. **Irregular** [Hok74]. **Irving** [Sym71]. **Irwin** [Bon77, Gra72]. **Isaac** [Bon76b]. **Iterative** [Cha72, HG73, Pre71]. **IV** [AT79, J.77h].

**J** [Add79, Ano74e, Bha72, Bis72a, Boa79a, Bon77, Bow78, Cle72a, Cro71, Dud79, Dyk76, Gil74, Gol74, Gou73, Gra72, Gri73, GH75, Ham75, Hea78, Hei76, J.75h, J75e, J.75a, J.75f, J.76b, J.76a, J.77f, J.77e, J.77l, J.77j, J.77q, J.77p, J.78p, J.78m, J.78j, J.79u, J.79m, Jer70, Jon73, K.71b, K.73b, K.73c, Kal75, Kle77, Law75b, Odo77, Ram73, Rog70d, Sax72, Sch74b, Sha71, Sid75, Sim79, Smi76, Spr72, Sta70, Ton72, Web73, Zie78]. **Jack** [Kup71]. **Jackknife** [Dun78b, GC79, Sal75a]. **Jackknife-Constructed** [Dun78b]. **Jackknifing** [Hin77b]. **Jackson** [Ano80a]. **Jagers** [K.74b]. **James** [Bel70, Qua74b, Qua74a, vdV75, DV79]. **James-Stein** [DV79]. **Jan** [Bak74, Hun74, K.71b]. **Jean** [Joh73c]. **Jenkins** [Ran70c, Kle77]. **Jerome** [And75]. **Jerzy** [Fre73b]. **Jessen** [Jon73]. **Joan** [J.79p]. **John** [Ano74e, Boa79b, Boy74, Cas76, Fre73a, Gle78, J.77b, J.77d, J.77o, Joh75, K.71e, Lac72a, Leh71, Qua74b, Qua74a, Add72, Cro71]. **Johnson** [Che71, Cru78b, Fre74a, Smi70a, Spr78, Dav70, Dun77a, Kin79b]. **Joiner** [J.78g, K.71a]. **Jonckheere** [Ode71]. **Joseph** [Con74]. **Journals** [K.71a]. **Judah** [Hog74]. **Judge** [Wil79a]. **Judgments** [Gru73a]. **Judith** [J.79k]. **Julius** [Har75, Hog74].

**Kabe** [K.74c]. **Kagan** [Sen75]. **Kali** [Ben76]. **Karl** [Jac80]. **Kathleen** [J.75c]. **Kay** [Ber73]. **Kececioglu** [Ziz78]. **Keeney** [J.78b]. **Kemeny** [Ham75]. **Kendall** [Fie73]. **Kenneth** [K.73c, Sch74b]. **Kernel** [BMP77]. **Kimble** [Kin79b]. **Kinetic** [PDB77]. **King** [Hay73, Kno71]. **Kleindorfer** [J.79d]. **Knowledge** [ABA72, Jac80, Rah76]. **Known** [MD71, Ste78]. **Kocherlakota** [J.75c]. **Kodell** [Smi76]. **Kolchin** [Spr79]. **Kolmogorov** [BD73, DM78, LR78, PS77]. **Kolmogorov-Smirnov** [BD73, LR78]. **Konijn** [Ste75]. **Koosis** [Boa79a]. **Kossack** [Gro77]. **Kotz** [Che71, Fre74a, Smi70a, Spr78]. **Kreyszig** [Cor71]. **Krishnaiah** [J.77h, J.78a, J.79g, J.79f]. **Kruskal** [J.79k, Lac74a]. **Krutchkoff** [MK70]. **Krzyz** [Hun74]. **Kshirsagar** [Ing78b, Kha74]. **Kumar** [Ban73, Ano71g]. **Kurtosis** [JL79, Rou73].

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[Ber72b, Che71, Con74, Cro78, Cru78b, Dav70, Dun72, Eas72, Fed77, Fre73b, Fre74a, Gow72, Gua71, Ham75, Har72, Hol73, Hun70, J.75g, J.76b, J.76h, J.78l, J.78g, J.78b, Joh71b, K.71a, Kab74, Lac71b, Lan75, Mer79, Qua74b, Qua74a, Rog70b, Ron72, Rus73, Sal75a, Smi70a, Smi76, Spr78, Wei71, Woo74b]. **L.** [GW71]. **Laboratory** [TB75]. **Lack** [Ano72f, DH71]. **Ladany** [J.77i, J.78e]. **Lagrangian** [Gre70a]. **Lai** [K.71c]. **Lancaster** [Ros75a]. **Large** [AM79, Cha79, CR79, Gut73b, HD70, Jae76, WG79]. **Larger** [Lad77].

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How77, Ing78b, J.76g, J.76f, J.76i, J.78h, J.79k, J.79v, J.79m, Kal75, Kha74, Lac71a, MRR78, Odo77, Ran70c, Rog70a, Sen75, Sim76, Urq73, Wil79a]. **M-Estimator** [MRR78]. **Machine** [WB75]. **Machol** [J.78e, J.77i]. **Madan** [K.71c]. **Main** [CDR79, DR77, Dic74, Nai74]. **Main-Effect** [CDR79, DR77]. **Maintain** [Dun78a]. **Maintainability** [Ziz78]. **Maintenance** [RR76]. **Majorization** [Low70]. **Making** [J.78h, Kin78, Win71]. **Malik** [Sch74b]. **Management** [Gua71, J.78p, Ziz78, Dun77b, J.78e]. **Mantel** [AK71]. **Manual** [Ziz78]. **Manufactured** [Kao72]. **Many** [Ros75b, Ros77]. **Maps** [J.79l]. **Marc** [Fre73a, J.77a]. **Marcel** [J.79b]. **Mardia** [J.79u, Wat73]. **Marginal** [Par70]. **Margolin** [Ano70f]. **Mario** [J.75d]. **Market** [Nay72]. **Markets** [Kno71]. **Markov**
[Cra74, Sys75, AvdL70, Bri74, JK74, WB71, Doo72, Sys76]. **Marquardt** [SS71b]. **Marvin** [Mye74]. **Mask** [Luc73]. **Massey** [Wei71]. **Material** [BF72, Lev79]. **Mathai** [J.79v, Sim76]. **Mathematical**
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[And73, Ban73, GZ79, GC74, Urq73, Zys70, Gow72]. **Matrix**
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[Ano76e, Beh70, BF72, Cha79, Cor75, CO75, Cor77, CK79, GK77b, Har79, Joh70c, Joh70b, MS74, Par78b, Ray72, Sch71a, Sne73, SM74, Sne75a, Sne75b].
**Mixtures** [Cor73, Cor79, DJ77a, DJ77b, Gri70, LC70, SN77, SM76, GK77a].
**Model** [Ano72g, Ano73j, Ant77, BDH70, Bri74, CF77, CS76, Cor77, DJ77b, GLV74, Gue71b, HBA71, Hah72, HH73, HP71, Hil78, HJF78, HM73, Leo75, Man71a, Mar73, MW78, MHC77, MPB70, MA78, Nai74, OM72, Par78b, Pas79, Rah76, RR76, SWD70, SB72b, Tar76, TA75, TC73, WK71, WB74, WG78, Wio70, GDF78, J.75d]. **Model-Discrimination** [MPB70]. **Modeling**
[LS71b, LSM72, PW77, Sch75]. **Modelling** [MPBD79, J.79m]. **Models**
[Ano76e, BK70a, BG78, BL73, Cle71, DJ77a, DAH73, Dun74, Fuc78, GK77b, Goo71, Gri79, GPS73, Har73a, Har73b, Hel74, HM77, K.71d, Lac74b, LR76, Lun75, MS74, MW73, Mer72, Par78a, Par78b, Pre75, PDB77, San72, San73, See73, SM74, Sne75b, Sne77, Spr76, Spr78, SWD74, TW72a, Wol78, Boa73, Boa79b, Hul73, J.75a, J.76g, Ron72, Smi77]. **Moderate** [Gut73b, MF77].
**Moderate-Size** [MF77]. **Modern** [Dun77b, Spr78]. **Modes** [Beh70].
**Modification** [Dav79a, Mie74, SOE75]. **Modifications** [Zah75b]. **Modified**
[DM78, KM79, Koy78, Lin79, Luc73]. **Modular** [Bod70]. **Modulus** [SU79].
**Molenaar** [Hel71a]. **Moments** [Cha70b, Gro71b, Jae74]. **Monotone** [Sen74].
**Monotonicity** [Gro71b]. **Monte** [Rel70]. **Montgomery** [Dun77a]. **Moore**
[Hub78]. **Morris** [Kin78, Ran70b, Win71]. **Morrison** [J.78e]. **Mortality**
[MS73]. **Most** [Ala71, Bli72, EB77b]. **Mosteller** [Lac74a, Qua75, Odo77].
**MOSUMS** [BH78]. **Motion** [CF76, Nád73, PK76, Ser73, SS74]. **Motions**
[HM73]. **Moving** [CK75, RH78, Ste72b, SWD74, Wic72]. **MR** [Kit81].

**MTBF** [BS79]. **Mullen** [Sch74b]. **Multi** [Coh75, HP71, Sac72]. **Multi-Censored** [Coh75]. **Multi-Level** [Sac72]. **Multi-Risk** [HP71]. **Multicollinearity** [WW78]. **Multicomponent** [SCSB76]. **Multidimensional** [CR79, Goo71]. **Multifunctional** [Sac76]. **Multinomial** [AA74, Ang74, BK70b, OL77, Ten72]. **Multinormal** [HS72]. **Multiple** [Ait74, And74, Bea70, FH79, Goo71, Gor76, HG73, Haw72, LSYF79, SP74, SU79, Ury76, VM79, WB71, Cle72a, J.77g, J.78h]. **Multiplicative** [SOE75, YC78]. **Multiresponse** [BDH70, BHME73, Gri73, MPBD79]. **Multivariate** [BMP77, Cha79, Dun72, Fre74a, Gaf78, GG70a, Gut73a, HB71, J.78f, J.79i, McK79, Mil72b, Odo77, Pat73, Reg76, Ron77, Ger75, J.75c, J.76d, J.76e, J.77h, K.74c, Kha74, O'F73]. **Murdoch** [J.78p]. **Muse** [Ano79e]. **Mutually** [BCK61, Hed71, BCK78]. **Myers** [Rus73, Fed74a, Man73]. **Myint** [Cha75a]. **Myint-U** [Cha75a].

**N** [Bis72b, Che71, Dav70, Geo72, Gri73, J.75a, J.77n, J.77j, J.79t, J.79h, K.71a, Sim76, Smi70a]. **Nadler** [Buc73]. **Namboodiri** [J.79t]. **Narayan** [Hei79]. **Narula** [Ano80b]. **Nash** [J.77b]. **Naslund** [Dun77b]. **Natural** [Ens78]. **Naylor** [Mer72]. **Near** [AT79]. **Nearly** [Har74]. **Negative** [BG74, Bin74a, Gru71c, Gue72, MC72, Nel75, Pie73, Ron77, GH75]. **Nelder** [K.71e, ON75]. **Nerlove** [Fre73a]. **Nested** [Ede74, GG70b, OL77, TA75]. **Net** [Bin74b]. **Network** [Gor76, Mar75]. **Neutral** [Sta79]. **Neuts** [J.79b]. **Newton** [JS76]. **Neyman** [Fre73b]. **Nigel** [Lut73]. **No** [Bor72, Har73a, LvNN73, Mal74, Mar74, Par72, Zel72, GH75, HK77, Kit81, Smi76]. **Noether** [McC72, Mer77]. **Noise** [Shu71]. **Nomogram** [GW71]. **Non** [BC71, BH77, GPS73, HG73, J.77b, Joi77, Krz77, Lac74b, Man71a, Pep73, RSO72, Ron77, Tak72, TA71, Weg74, WB75]. **Non-Additive** [Man71a]. **Non-Interactive** [BH77]. **Non-Iterative** [HG73]. **Non-Linear** [GPS73, J.77b]. **Non-Negative** [Ron77]. **Non-Normal** [Tak72]. **Non-Normality** [RSO72, TA71, WB75]. **Non-Optimal** [Krz77]. **Non-Orthogonal** [BC71]. **Non-Random** [Lac74b, Pep73]. **Non-Standard** [Joi77]. **Noncentral** [MCL76, KP79]. **Noncentral-F** [MCL76]. **Nonlinear** [BD72a, BL74b, BDH70, Box70b, BL73, DV78, Dun78b, LS71a, LSM72, LvNN73, Mar70, NV73a, NV73b, RJ78, Sac76, Sha71, SS71b, Cha75b]. **Nonlinearity** [LaB77]. **Nonorthogonal** [HK70a, HK70b]. **Nonparametric** [Ano80c, BR79, Bha72, Cho73, McD79, Mer77, Weg72, Dun72, Gib74, Joh73c, K.71c]. **Nonparametrics** [Qua75, Mer79]. **Nonrandomized** [MDM77]. **Nonstationary** [HM73]. **Norbert** [Kab74, Rus73]. **Normal** [Aus73, Beh70, BR73, CC71, Cha79, Coh76, Dow73, DA73, FD70, FM77, GG70a, GW71, Gri70, GS71, Joh70c, LNN61, MD71, McM71, Mil72b, MM73, Nád71, NK76, NS79, OlHS77, RSO72, Ray72, Reg76, Riz71, Sor73, Tak72, WK77, Zah75a, Zah75b, LH77]. **Normality** [Ano75e, Fil75, Kow70, RSO72, TK72, TA71, WB75]. **Normalizing** [WY78]. **Norman** [And70, Cru78b, Fre74a, Spr78]. **Note** [AM79, Ano73i, AK71, Bai74a, Bea70, Bis78, Con70, Cro71, DR77, DL70,

DY70, Eva71, Fau70, Fra77, Hal77a, Haw72, HK75, JK71, Kap72, Ken71, Lac79, MH72, MW75a, Ng76, Sch70, SS71a, Sne71, Tho75, Ton74, Ton75, JTS75]. **Notes** [Coo72]. **Nuclear** [BKRS78, HS71, J.78j]. **Nuisance** [EB77b]. **Null** [LF79]. **Number** [Dic74, Gru73a, Gue71a, Wio70, Wol78]. **Numbers** [Ben76]. **Numerical** [AB74, CR79, Dil71, Dun78a, Eva71, Eva72, Lin74, RH78].

**O** [Hac78, HH73, Ron72, Ros75a, Sie75, Sne74]. **Objectives** [J.78b]. **Objects** [Ens76]. **Observable** [Nád70a]. **Observation** [Coo77, Joh70c, Joh70b, KS71, Lik74]. **Observations** [Ano73g, FM77, GB72, Joh70c, Joh70b, Man70a, Ray72, Sin71, TS79, BN72, HP73, Fre75, J.78f]. **Observed** [FB75, Har74]. **Obstructive** [Ens78]. **Obtain** [Gre70a]. **Obtained** [Sin71]. **Obtaining** [CK79, Gue77, Jae70, MF73]. **OC** [Kow71]. **O'Carroll** [J.79m]. **Occurrence** [Gre70b, Sap73]. **Odeh** [J.76g, J.78l, J.77k, J.78o]. **Odell** [Gow72, Ron72]. **Odoroff** [Ano77a, Ano79f]. **Olkin** [Dud79, Sid75]. **O'Muircheartaigh** [J.77m]. **One** [Bai73, FM77, GLV74, GPU76, HP73, Hoc72, JD78, KB75, Kus79, Lad77, MD71, McM71, MM73, Rah76, SS75, SD77, Wes71, Boa79a]. **One-Four** [Boa79a]. **One-Sided** [FM77, SS75, Wes71, GPU76, HP73]. **One-Way** [Kus79]. **Only** [CHH$^+$71, Nád70a]. **Operates** [DY70]. **Operating** [BM76, Ell76, PW77, SLK79]. **Operation** [And70, Wan71]. **Operational** [J.79n]. **Operations** [J.77a]. **Opinion** [Gle78]. **Optimal** [Ano77h, BN72, Bis72b, BH77, EB78a, Gor76, Gre70a, Har74, J.79d, Jon76a, Krz77, Luc78, Mac76, MW78, MCM75, Mit74a, Mit74b, MB78a, MB78b, Sim73, Sor72a, SC71, Gor76, J.77i, Ran70b]. **Optimality** [JD75, NGM70]. **Optimally** [Kam72]. **Optimization** [Bro79, HS73]. **Optimum** [BS72, CF76, HS72, Law77b, Luc74, MG74, MH77, NK76, NM78, PK79, Sch71b, GK77a]. **Orbital** [Bus71]. **Order** [Ber72a, BMH76, BD74, Gue77, Hed71, Hok74, JC76, Kal75, Kam72, Kam74, Mit74b, OM72, Qua75, SWD70, SWD74, TW72b, Weg74, Gru71a]. **Ordered** [Lik74, Man70a, Ode71]. **Ordering** [Dud79, Gar71]. **Orders** [Dic74]. **Ordinary** [MHL77a, Sac75]. **Organisms** [Car77b]. **Origin** [Joh70c, Joh70b, Ste78]. **Orkin** [Car77a]. **Orthogonal** [BC71, BCK61, CDR79, DR77, Hed71, BCK78]. **Osborne** [Lac71a]. **Ostle** [Gle77]. **Other** [J.79v]. **Otnes** [Nel74]. **Outlier** [Ano74f, JD78, Jos72, KS71, Ros77, TMB73]. **Outliers** [Ano79g, GW75, GS71, Gut73b, JD78, JMM78, Kit79, LF79, Lun75, MD71, McM71, MM73, Pre75, Ros75b, Ste72a, TM72, GDF78, Kit81]. **Outliners** [Gut73a]. **Outlying** [Ano73g, GB72]. **Output** [MBC79]. **Over-Stress** [Law77b, Man72, MH77]. **Owen** [J.77k, J.78l, J.78o, Har72, J.75g, J.76h, J.78k, Tan70].

**P** [Add79, And70, Dav70, Dun72, Fle76, Gow72, GH75, Hea78, Hil74, J.75b, J.77n, J.77i, J.77h, J.78e, J.78q, J.78a, J.79g, J.79d, J.79u, J.79f, Jon76b, K.71d, K.74c, Kle77, Lac72b, Law75b, O'F73, Qua71, Ram73, Ron72, Sax72,

Sim76, Sne70, Spr79, Ton72, Zac74]. **Pacemakers** [BKRS78]. **Packages** [Hub78]. **Packing** [GLV74]. **Pair** [Nád71]. **Pairwise** [Ury76]. **Paliouras** [Cas76]. **Panne** [For73]. **Paper** [Fed75, MK70]. **Papermaking** [TW72a]. **Papers** [Ano70a, Fie73, HM71, J.77l, K.73d, K.73b]. **Paradoxes** [Lut73]. **Parallel** [Bry71, Wan71]. **Parameter** [AvdL70, AJ77, BE73, Bec74, Box70a, BM76, Cha75b, Coh75, Coh76, CN77, CM71, DG71, Dun78c, Dye73, Eas76, Ell76, EB74, EB75, EB77b, EB78c, GHW79, Gru71c, Kam72, Kam73, Law77a, Lem75, Lik74, Low74, Man72, MF75a, Man75, Mat78, MC72, O'B73, Pas79, Pie73, RRH73, Rou73, TW72b, GPU76]. **Parameterizations** [Sin73]. **Parameters** [Ano73k, BD72a, BL74b, BL73, D'A71a, D'A71b, DAH73, Eng75, EB78a, Fal70, Fin76, Har73a, Has72, HH74, Jae70, Kam74, Kap75, LS71a, Man70a, Man71b, MF73, MF75b, OB76, Par78b, Pat76b, RS71, Rah76, SG71, SR75, Wio70, LR78]. **Parametric** [Rog70a]. **Parent** [YM74]. **Parking** [GLV74]. **Part** [Zel72, NH72, NH73]. **Partial** [LM72, Cha75a]. **Partially** [Har73b]. **Particles** [GLV74]. **Partitioned** [Far78]. **Partitioning** [CR79]. **Passage** [CF76, Nád73, PK76, SS74]. **Path** [Bur73]. **Patil** [K.71d]. **Patterns** [BD72b, Cor77, Dan78]. **Paul**
[Ber73, Eri72, Gil74, Joh71b, Jon73, Kin79b, Odo77]. **Payne** [J.77m]. **Pearson** [Sne74, Har71]. **Penalty** [Gre70a]. **Categorical** [J.79c]. **Percentage** [Ano73g, GB72, Gue77, Har71, IM70, KB75, Krz79, Ros77, Som70, YM74, TC72]. **Percentages** [RSO72]. **Percentiles** [CC71]. **Performance** [BJ75, Dub73, Jae74, JB74, KKM79, Kow70, Krz77, Luc76]. **Permuted** [J.77f, J.77q, K.71a]. **Peter**
[Add72, Fre73c, J.77c, J.79l, K.73e, K.74b]. **Peto** [Ens78]. **Phase** [BC79b]. **Phenomenon** [Bry71]. **Phillip** [Fin75, Str75]. **Physical** [Cru78b, Bis72a]. **Physics** [Cha75a]. **Piersol** [Har75]. **Pieters** [Lac74a]. **Pietro** [Qua71]. **Pisani** [Kin79a]. **Pitfalls** [BK74]. **Pitman** [MC72, J.77l]. **Pitman-Type** [MC72]. **Plackett** [Fed77, Wat70a]. **Plan** [Joh70a, KO77, SP72]. **Planning** [Dan70]. **Plans**
[Ano72g, BLB73, BS79, CDR79, DR77, Dic74, Gue71a, Gue71b, Hal77a, Hal79, Lad77, MCM75, MH78, PS70, Sac72, SP74, SP77, Sha79, Tak72, VM79, WB71]. **Plot** [Ano75e, Fil75, Zah75a, Zah75b]. **Plots** [LaB77, LM72]. **Plotting** [Nel72b]. **Pocket** [J.78l]. **Point**
[BD74, EB74, Fre73c, MF75b, WK71, And75, J.75d]. **Points**
[Ano73g, GB72, Gue77, Har71, IM70, Joh79, KB75, Krz79, Man75, Ros77, Som70, YM74, TC72]. **Poisson** [Hel71a, AT73, Coh72, CM71, CJ73, GH70, Ham72a, Jae70, Man75, Nel75, Pat73, Pat76b]. **Policies** [Sch71b, TC75b]. **Policy** [BS72, Jac80]. **Policymaking** [Jac80]. **Political** [Lut73]. **Pollution** [Ano73j, Boy74, CG76, Mar73, MS73, Sin72]. **Poly** [Kle75]. **Poly-Factor** [Kle75]. **Polynomial** [Cor75, Gaf78, LW71, Par78a]. **Polynomials** [Mal74, Mar74, BT74]. **Population**
[Beh72, BSH71, FM77, HG78, Joh70c, Joh70b, McD76, RRH73, SR75, Zac70]. **Populations**
[Ano73k, Dud79, Gro72, Joh70c, Joh70b, Ray72, Reg76, SS76, vN79]. **Port**

[Gil74, Sax72, Ton72]. **Portable** [BK74, Whe74, Whe75]. **Positive** [Bin74a, CF76]. **Possible** [CBI79, Fur71, MT72, Sta79]. **Postulated** [SLM74]. **Potential** [BK74, Sys75]. **Power** [BJN71, BK74, BH74, Bri73b, DW72, Dub73, FR72, For72, GC74, HK75, KARR75, LH74, Mal74, Mar74, PK76, PK79, Whe74, Whe75, Yue78, BT74]. **Powered** [BKRS78]. **Powerful** [EB77b]. **Practical** [NGM70, Bha72, Sie75]. **Practice** [Ben76, J.79m, Odo77, Pre77]. **Practices** [Eas72]. **Pranab** [Kee75]. **Pratt** [Boy74]. **Pre** [Wil79a, Rah76]. **Pre-Test** [Wil79a, Rah76]. **Precision** [Ben76, Dan70, Gru73b, Jae76]. **Prediction** [All71, All74, AM79, BSH71, Cle71, CK79, EB78b, EB79, FM77, GM79, Hah72, Hah75, Hah77, HM76b, KN74, Kam77, Law71, Law77a, Lik74, MF77, NW77, SS71a, HP73, Boa79b]. **Predictive** [Dun74]. **Predictor** [LvNN73, NV73a, NV73b, Rub76]. **Prekopa** [K.74a]. **Preliminary** [McD75, Obe75]. **Premium** [Gut73b]. **Prescribed** [Dan70]. **Presence** [GR72, JMM78, KS71]. **Present** [Jos72]. **Presented** [Ano70a]. **Preservation** [Luk73]. **Previous** [Nel72a]. **Price** [Hah79]. **Prices** [Kno71]. **Primer** [Gie74]. **Principal** [JH73a, JM79, JH79, Krz79, Wol78]. **Principles** [Car77b, Cor71, Han73]. **Pringle** [Urq73]. **Prior** [ABA72, Ano72g, Chi74, Gro72, Gue71b, PS70, Rah76]. **Probabilities** [Dun71, Sor72a, Sor72b]. **Probability** [Ano75e, Bad70, Bor72, Bur73, Fil75, Fre73b, GH70, Hac78, Hac79, Hei79, Hol75, J.77d, J.77f, J.77e, J.77l, J.77o, J.77q, J.77p, JR72, Joh71b, K.73e, Kap72, LaB77, Lac71b, Law77b, MH77, MH78, Moe72, RTDM79, Rog70d, Sam73, ST72, Sch74b, Sid75, Smi77, Sne70, Sor71, Sor73, Spe71, Spr78, Sta70, Sym71, Ton72, Weg72, Woo74b, Zac74, Bis72a, Har70, J.78k, J.79b, Mil72a, Rog70c, Zie78, Bow77, Fed74a, Gol74, Hei78, Hog74, How77, J.76f, Kup71, Lan73, Ram73, Rog70b, Wei71, Zac74]. **Probable** [Ala71]. **Probe** [JK74]. **Probit** [Gou73]. **Problem** [AT73, AF76, Gri72, HN70, Haw72, Hel74, Kal71, KA71, Law71, Lem74, MW75b, MRR78, Ray72, Ros75c, Sam78, Shu72, Wat74, LH74]. **Problems** [And75, BC71, BHME73, EB79, Gue74, HK70a, HK70b, McL74b, Riz71, Sen75, Sin72, Whi70, Boy74, J.77b, Hun74, J.79o]. **Procedure** [BR79, BKRS78, Bin74b, Bis78, Bli72, Cha72, GG70a, GR72, KKM79, MB74, O'B73, ON75, RRH73, Ros77, SR75, SS71b]. **Procedures** [Ano73a, Ano80c, Bea70, Ber78, BD78, CF76, CG76, EB77a, EB78a, FH79, Gle78, Goo71, Gut73b, Hil78, Igl73, JM79, LSYF79, LO79, Man70b, McD79, McK76, PW72, Pre71, Reg76, SS76, Ury76, Eas72, Har75]. **Process** [Ano77h, BR79, Coh72, CM71, DS79, Dun78a, EB78b, Fin76, Har79, HD70, LL78, Mac76, TW72a]. **Processes** [AvdL70, AT73, BGH73, Fre73c, Rog70b, Gil74, Sys78]. **Processing** [Gle78]. **Product** [DS79, Hah77, Kao72, OB76, YC71, Ziz78]. **Production** [Bla77, DS79, Sha79]. **Productivity** [And70]. **Products** [Hay73]. **Progamming** [AA74]. **Program** [Wat70b]. **Programmed** [Boa79a]. **Programming** [AK71, For73, Ran70a, Sie75, Sys75, Coo72, Gro77, Lin75, Sha71]. **Programs** [Hea78]. **Progress** [Ano76f, J75e]. **Progressive** [Man71b]. **Progressively**

[Coh76, CN77, TW72b]. **Proper** [BJ70b]. **Properties** [Bry74, Gro71b, Joh70a, Low76, Spr76]. **Proportion** [Wio70, Zac70]. **Proportional** [Nád70b]. **Proportionality** [Man75]. **Proportions** [AB71, BR75, BM78, Cho79, MDM77, Con74]. **Proschan** [J.75f, Smi77]. **Protection** [Gut73b]. **PrY** [Ury72]. **Psychological** [Ger75]. **Publications** [Ano75k, Ano76k, Ano76l, Ano76m, Ano76n, Ano77m, Ano77n, Ano77o, Ano77p, Ano78k, Ano78l, Ano78m, Ano78n, Ano79l, Ano79m, Ano79n, Ano79o]. **Pure** [Kee75]. **Puri** [Dun72, K.71c]. **Purpose** [ST73]. **Purves** [Kin79a].

**Quadratic** [Ano76e, AK71, GK77b, Lac79, Luc76, Roq76, Sne75b, SS78, TC73, Yue78]. **Quadruple** [Pat76b]. **Qualitative** [J.79c]. **Qualitative/Categorical** [J.79c]. **Qualité** [Gua71]. **Quality** [BH78, DS79, Gua71, Pat73, ST73, Tsi78, Ziz78, Kab74, Woo75]. **Quantile** [MF77]. **Quantiles** [Dye73, Has72, Kam73, SA79]. **Quantitative** [Gri73, Sto76]. **Quartic** [Mat78]. **Quasilinearized** [KME71]. **Quasimidranges** [LC70]. **Query** [Bad70, Bor72, Leo70, Wat70a].

**R** [And70, Bow78, Bri73a, Fed74a, Fed77, GW71, Gor76, Gri73, Hog74, Hul73, Ing75, J.75b, J.75f, J.76g, J.76d, J.76e, J.77j, J.77k, J.77h, J.78l, J.78e, J.78f, J.78d, J.78m, J.78j, J.78b, J.78a, J.78o, J.79g, J.79r, J.79o, J.79v, J.79d, J.79f, J.79m, K.73b, K.74c, Kal75, Kin79b, Kup71, Lac71b, Lac71a, Lac74a, Law75b, O'F73, Sal75a, Sen75, Smi76, Sne76, Urq73, Weg76]. **R.** [MK70, J.79p]. **Rade** [K.74b]. **Radhakrishna** [Ban73]. **Radium** [PBT76]. **Raiffa** [J.78b]. **Rainville** [Fin75, Str75]. **Raj** [Sen70]. **Ralph** [Rog70b]. **Ralston** [J.79q]. **Ramachandran** [Sen75]. **Random** [Bag70, BL71, BK70b, Bri73a, Cha70b, GLV74, HW75, J.78q, Kus79, Lac74b, Nád70a, Nai74, Pep73, Rog70b, TA75, WY78, LH77, Har75, K.71d, Spr79]. **Randomization** [TW70, You72b]. **Range** [Fed75, FKRO71, GKS75, Nea70, Smi76]. **Ranges** [McD76]. **Rank** [Ano84, BJN71, GZ79, IC79, Kra76, Mie74]. **Ranking** [AT73, BR79, Bis78, SR75]. **Ranks** [HM77, Mer79]. **Rao** [Ban73, Sen75]. **Raphson** [JS76]. **Rasch** [Ens77]. **Rate** [Bai74b, Dan70, FR72, HH77, LR76, LE73, McL74b, Sha78]. **Rates** [Ano80c, Bry71, Con74, McD79]. **Rathie** [Sim76]. **Ratio** [BL71, Dav79a, DAH73, Har73a, Jae70, ST72]. **Rationality** [Lut73]. **Ratios** [BK70b]. **Ratti** [Spr72]. **Ray** [Sau73]. **Raymond** [Jon73, Kno71, Man73]. **Rayner** [Urq73]. **Re** [Sin73]. **Re-Parameterizations** [Sin73]. **Reaction** [SLM74]. **Reactor** [HS71]. **Readings** [Fre73a, K.73c, Qua71]. **Real** [Boa79a]. **Reasoning** [Hac78]. **Received** [Ano75k, Ano76k, Ano76l, Ano76m, Ano76n, Ano77m, Ano77n, Ano77o, Ano77p, Ano78k, Ano78l, Ano78m, Ano78n, Ano79l, Ano79m, Ano79n, Ano79o]. **Reciprocals** [BK70b]. **Recognition** [Dol70]. **Recorders** [Nea70]. **Recursive** [LF79]. **Reduction**

[Gen77, Par78b, Rel70, Ens76]. **Redundancy** [Gre70a]. **Redundant** [TC75a]. **Reflected** [Coh73]. **Regime** [Rif71, WB74]. **Regions** [Dun78b, Luc76, Obe77, LR78]. **Regression** [Ait74, ABA72, And74, Ano74f, Ano84, BC71, Bea70, BL74b, Ber78, Bro77, Coo77, Cro78, DM77, Dun78b, Far75, Far78, For72, Fra77, Gaf78, Gor76, Gre71, GWM76, Hah72, Hal70, Haw75, Hem75, Hil78, HJF78, Hoc72, HSL76, HK70a, HK70b, HK75, HR75, Hoo79, IC79, J.75d, JD75, KME71, LH70, LM72, LS71a, LSM72, Mar70, MK70, MS73, McK79, MHL74, MHL77a, MHL77b, NW77, NW79, NH72, NH73, Obe77, Par70, Par78a, PW72, Rah76, Sac76, SH79, SS71a, Sne77, SD77, TMB73, WGM74, WG79, Wio70, YF76, Zel72, DV79, Ell78, McC78a, For71, Fre75, Hah79]. **Regressions** [BC79b, DH74, Fur71, FW74, MT72, Rub76, SS71b]. **Regular** [Ber72b, Gue72, TS79, GH75]. **Reinhardt** [Hac78]. **Rejecting** [Ste72a]. **Related** [Ano72e, Ano73h, BD71, For73, J.79u, JS76, Wol77a]. **Relating** [MS73]. **Relations** [Haw75]. **Relationship** [All74, McL74b, NH72, NH73, Zel72]. **Relationships** [CH70, JH73a]. **Relative** [LR76, NW77]. **Relevant** [YC71]. **Reliability** [Bha73, BGH73, Bod70, Bri74, BWL78, CB75, CH70, DY70, EB78c, FB75, Gro71a, Gru71b, Gru71c, HBA71, Hei76, Her70, HM76b, J.78j, MG74, Pie73, Rea71, Sar71, Smi77, TBA70, TC75a, Var70, WK71, WG78, Whi70, Ziz78, J.77n, Kab74, Eas72, J.75f, J.77j]. **Remark** [Rea71]. **Remarks** [AvdL70, Nel75, SB72a]. **REML** [CS76]. **Renewal** [BGH73, HD70]. **Renyi** [Rog70c]. **Reordering** [BS72]. **repair** [Bha73]. **Repairing** [HM72]. **Replacement** [CH74, IS76, RR76, Sch71b, TC75b]. **Replacements** [IR77]. **Replication** [Gre71]. **Report** [Ano74g, Co.72, Com70, Com71]. **Representation** [Lac71a]. **Required** [SdV73]. **Requiring** [Dic74]. **Research** [Cha70a, Gle78, J.79n, Ger75, Gle77, J.77a, Lac72b]. **Residual** [LM72, MT72]. **Residuals** [BD72b, Dan78, DL70, GW75, JM79, Nel73, Sne71, Woo73]. **Resolution** [AT79, LS71b, SC71, SLM74]. **Response** [CP75, CO75, HM72, HS73, Luc76, MB78b, MC73, ML75, Roq76, Sne72b, Sne75a, Nay72, Man73]. **Responses** [Sta79]. **Restricted** [AF76, CS76, Joh70a, SN77, Wat74]. **Restrictions** [Kal75]. **Results** [Bai73, BB79, Bis79, DM78, Dun78a, EB73, EB74, Hol75, LL78, McL72, Nel72a, Weg74, YC71]. **Review** [Add72, Add79, And70, And75, Ano71f, Ano74e, Bak74, Ban73, Bed74, Bel70, Ben76, Ber72b, Ber73, Bha72, Bis72a, Bis72b, Boa79b, Bon76a, Bon76b, Bon77, Bow77, Bow78, Boy74, Bri73a, Buc73, Cam77, Car77a, Car77b, Car74, Cas76, Cha75a, Cha75b, Che71, Cle72a, Con74, Coo72, Cor71, Cor73, Cra74, Cro78, Cru78a, Cru78b, Dal77, Dav70, Dav77, Dil71, Doo72, Dra79, Dud79, Dun72, Dun77a, Dun77b, Dye74, Dyk76, Eas72, Ehr77, Ens76, Ens77, Ens78, Eri72, Fed74a, Fed77, Fie73, Fin75, Fle76, For71, For73, FW72, Fre73a, Fre73b, Fre73c, Fre74b, Fre74a, Fre75, Gen77, Geo72, Ger75, Gib74, Gie74, Gil74, Gle78, Gle77, Gol74, Goo75, Goo76, Gor76, Gou73, Gow72, Gra72, Gri73, Gro77, Gru71a, Gua71, Hac78, Hac79, Hah79, Hal77b]. **Review**

[Ham75, Han73, Har77, Har70, Har75, Har72, Hay73, Hea78, Hei76, Hei78, Hei79, Hel71a, Hel71b, Hil74, Hil78, Hog74, Hol73, How77, Hub78, Hul73, Hun70, Hun74, Ing75, Ing78a, Ing78b, J.75d, J.75c, J.75g, J.75b, J.75h, J75e, J.75a, J.75f, J.76c, J.76b, J.76g, J.76d, J.76e, J.76f, J.76a, J.76i, J.76h, J.77b, J.77d, J.77f, J.77e, J.77l, J.77c, J.77n, J.77j, J.77g, J.77m, J.77i, J.77k, J.77h, J.77a, J.77o, J.77q, J.77p, J.78n, J.78h, J.78l, J.78k, J.78e, J.78f, J.78g, J.78d, J.78p, J.78q, J.78i, J.78m, J.78j, J.78c, J.78b, J.78a, J.78o, J.79q, J.79i, J.79p, J.79g, J.79e, J.79j, J.79c, J.79l, J.79r, J.79k, J.79o, J.79t, J.79b, J.79v, J.79d, J.79n, J.79a, J.79s, J.79u, J.79f, J.79h, J.79m, Jac80, Jer70, Joh75, JD75, Joh71b, JH73b, Joh73c, Jon73, Jon76b, K.71a, K.71d, K.71b, K.71c, K.71e, K.73d, K.73b, K.73c, K.73e, K.73a, K.74c]. **Review**
[K.74e, K.74a, K.74b, K.74d, Kab74, Kal75, Kee75, Ket75, Kha74, Kin78, Kin79a, Kle77, Kno71, Kra76, Kup71, Lac71b, Lac71a, Lac72b, Lac72a, Lac74a, Lan73, Lan75, Law75b, Leh71, Lev79, Lin75, Luk73, Lut73, Lyn78, Man71c, Man73, Mar75, McC72, McC78b, Mer77, Mer79, Mer72, Mih75, Mih77, Mil72a, Moe72, Mye74, Nay72, Nel74, O'F73, Odo77, Odo78, Pre77, Qua71, Qua74b, Qua74a, Qua75, Ram73, Ran70a, Ran70c, Ran70b, Rog70d, Rog70b, Rog70a, Rog70c, Ron72, Ros75a, Rus73, Sac75, Sal75a, Sam73, Sax72, Sch74b, Sch75, Sen70, Sen74, Sen75, Ser73, Sha71, Sid75, Sie75, Sim76, Sim79, Sim73, Smi70a, Smi77, Sne72a, Sne74, Sne76, Sne70, Spr72, Spr78, Spr79, Sta70, Ste75, Sto76, Str75, Sym71, Sys75, Sys76, Sys78, Tan70, Ton72]. **Review** [Tsi78, Urq73, Wat73, Web73, Weg76, Wei71, Wil79a, Wil70, Win71, Woo75, Woo74b, Woo74a, Zac74, Zie78, Ziz78, Zys70, vdV75, DV79, Ron72]. **Reviews** [Boa79a, Kin79b]. **Revised** [Zah75b]. **Revuz** [Sys76]. **Richard** [Boa79a, Car77a, Ens78, Gle77, Hub78, Joh75, Kno71, Odo77, Qua71, Smi77, Woo75]. **Ridge** [BC71, Bro77, DV79, Far75, Far78, GHW79, Haw75, Hem75, HB78, HK70a, HK70b, HK75, KM79, Mar70, McD75, Obe75, Obe77, WC78]. **Ries** [JK71]. **Ries-Smith** [JK71]. **Rising** [Lac74a]. **Risk**
[HP71, Hun70, J.78j]. **Risks** [Gru73a]. **Rivlin** [Jer70]. **Roach** [Man71c]. **Robbins** [Sim73]. **Robert**
[Cru78a, Hei78, Hol73, J.77i, Kin79a, Moe72, Nel74, Qua75]. **Roberts** [And75]. **Robin** [Con70]. **Robust**
[And74, CG76, Dav79b, DM77, For72, HM77, Law75b]. **Robustness** [Ano73a, HBA71, MHL77b]. **Rodger** [Sch75]. **Roessler** [Woo74b]. **Roger** [Kin79a]. **Rogers** [Law75b]. **Rohatgi** [Hac79]. **Romier** [J.78m]. **Romig** [KO77]. **Ronald** [Dye74, Har77]. **Root** [GWM76, WGM74, WG79]. **Roquemore** [Ano77f]. **Rosenblatt** [Hog74]. **Ross**
[J.77f, J.77e, J.77q, J.77p, Kin79b]. **Rotatable** [HP78]. **Roubens** [J.77a]. **Rough** [Kow70]. **'Round** [Con70]. **Rounding** [SB72b]. **Rourke** [Qua75]. **Roy** [Gri73, K.71e]. **Rozanov** [Sys78]. **RST** [Ros77]. **Rudolf** [Lev79]. **Rule** [AB71, Sor73, Wil79a]. **Rules** [GS71, Koy78]. **Run**
[Dic74, JC76, Rey75, RH78, VM79]. **Runs** [Bla77, Wat70a]. **Runyon** [Qua71]. **Rutemiller** [Bis78]. **Ruymgaart** [Kra76]. **Ryan** [J.78g, J.78g].

**S** [Add79, And75, Ben76, Bri73a, Cam77, Che71, For71, Gen77, Gra72, Gri73, Hah79, Har75, Hul73, Ing78b, J.75h, J.76f, J.78e, J.78p, J.79q, J.79d, J.79h, J.79m, Joh75, K.71a, K.74d, Lac71a, Lac74a, Lan75, Lin75, Mih75, Mih77, Sax72, Sim73, Sne72a, Sne74, Spr72, Ste75, Ton72, Wil70, KB75]. **Sachs** [Bed74, JH73b]. **Safe** [Law73]. **Sakarovitch** [Coo72]. **Sakradi** [J75e]. **Same** [Leo70, WK71]. **Sample**
[AB71, Ang74, Ano73g, Ber72b, BF74, BR75, BM78, BH73, CHH$^+$71, CC71, Cho79, DH74, Dye73, EB79, FD70, FR72, GH70, GB72, Gue71a, Gue74, Gut73b, Hah77, Has72, IM70, Jae76, JL79, Kam73, KB75, Lin74, NL75, Nel72a, Ode71, SdV73, Ste75, TJ79, Ury76, WG79, Wio70, Wol77b, J.76g]. **Sampled** [BF72]. **Sampler** [J.79a]. **Samples** [AM79, Ano73k, Bai73, BAB72, Coh65, Coh72, DM78, Ede74, GS71, Hah75, HS72, Kam74, Lac74b, Law71, Lem75, LF79, MF77, McL72, MD71, McM71, MS79, MM73, MHL74, MHL77a, NS79, OL77, SW72, Sin71, TW72b, Zei73, BD73]. **Sampling** [AB79, Ano72g, Ano77h, Aus73, Bai72, BL74a, Bin74b, BLB73, Car77b, Chi74, Coh70, Coh75, Coh76, CN77, Ehr72, Eld74, EB73, Gro72, Gue71b, HM76a, Hal77a, Hal79, J.78c, J.79t, Joh70a, KO77, Koy78, Lad77, Lev70, Mac76, PS70, Rel70, Sac72, Sch72, SP72, SP74, Sha79, Tak72, Ten72, VM79, Whe70, WB71, Zac70, J.79a, J.78n, Sen70, Tsi78]. **Samuel**
[Fre74a, Smi70a, Spr78]. **Sanford** [And75]. **Satterthwaite** [DW72]. **Saul** [Ran70a]. **Savage** [J.75h]. **Saxena** [J.79v]. **Scale**
[DAH73, Dye73, EB77b, Har73a, Kam72, Kam73, Kam74, LR78]. **Scaling** [Bro77]. **Scanning** [San72, San73]. **Scatterplots** [CK75]. **Schafer** [Bis78]. **Schatzoff** [Ano71g]. **Scheffe** [Par78b]. **Scheffé's** [Cor77]. **Scheme** [BJ70b, DS79, Gro72, Luc73, Rea71, Ron77, Ten72]. **Schemes** [Koy78]. **Scheuer** [Rea71, WG78]. **Schleifer** [Ham75]. **Schmidt** [J.77c]. **Schucany** [Sal75a]. **Science** [J.78e, J.78p, Jon76b, Bon76b]. **Sciences**
[Cru78b, Hei76, Leh71, vdV75]. **Scientific** [Bon77]. **Scientist** [J.79p]. **Scientists** [Boa79a, Cas76, Fed74a, Rog70b]. **Sclove** [Cro78, Lan75]. **Scope** [ML75]. **Scott** [Fre73b]. **Screening**
[Kao72, Kle75, LO79, MB74, OB76, OlHS77, Par78b, SM76]. **Seal** [Hun70]. **Sealed** [PBT76]. **Searle** [Hul73]. **Seber** [J.76c]. **Second**
[BD74, Hok74, OM72, SWD70, SWD74]. **Second-Order** [BD74, Hok74]. **Secondary** [Tho73]. **Seeding** [DV78]. **Segment** [Yue78]. **Segmented** [Par78a]. **Selected** [BMH76, Ing78b, J.75c, K.71a, Kam72, CGO07, Fre73a, Har72, J.75g, J.76h, J.77k, J.78o, K.73c]. **Selecting**
[Ala71, All71, MBC79, Par78b, RRH73, Dud79]. **Selection**
[All74, Ano80c, Bea70, GG70a, Gor76, HH77, Hel74, Hoc72, Kap72, LH70, Man70b, Man71d, McC75a, McD79, MRR78, NW79, Reg76, Riz71, Tho73]. **Selection-Multiple** [Gor76]. **Selection-of-Variables** [Hel74]. **Self** [Boa79a, LS71b, LSM72]. **Self-Teaching** [Boa79a]. **semigraphic** [Tuk70]. **Sen** [Ano70f, Dun72]. **Sensitivity** [Ant77, MHC77]. **Separate** [McL74b]. **Separating** [YB76]. **Separation** [Sch70]. **Sequence** [Rif71, LH77]. **Sequences** [HS71]. **Sequencing** [Bag70]. **Sequential**

[AS73, Aro76, Bar72, BS79, Cho73, CL70, CL71, DeG70, DS79, Ehr72, Igl73, IR77, KKM79, MB74, O'B73, PBT76, PS70, ST72, SI70, Ehr77, Fle76]. **Serfling** [J.75f]. **Serial** [BJ75, JB74]. **Series**
[AB74, BGH73, Cle71, Cle72b, Dav79b, Dun77a, Gru71b, J.79e, Kle77, LR76, Mal74, Mar74, MH72, Nel74, Par72, Pre77, Sar71, Shu71, Spe71, Var70, Weg76, BT74, Cle72a, Hea78, McC78b]. **Service** [Bag70]. **Services** [Hay73]. **Session** [Ano70a]. **Set** [CR79, Hed71, Leo70]. **Sets** [BCK61, BCK78]. **Sevast'yanov** [Spr79]. **Several**
[Ano79g, BF74, Gut73b, Luc76, TM72, BN72]. **Shafer** [Ing78a]. **Shape**
[AJ77, EB77b, FP77, O'B73, Rou73]. **Shaul** [J.77i]. **shift** [LH77]. **Shifts**
[Dav79b]. **Shimi** [J.77n]. **Shipman** [And75]. **Shooting** [And75]. **Short**
[Bla77, Cro78, Nel72a, Str75]. **Shortest** [AJ77, SS71a]. **Should** [Hoc72]. **Shrunken** [McD75, Obe75]. **Side** [See73]. **Sided**
[FM77, LO79, SS75, SdV73, Wes71, BN72, GPU76, HP73]. **Sidney** [Gil74]. **Siegmund** [Dav77, Sim73]. **Sigma** [Tak72]. **Sign** [Sta79]. **Signal** [Shu71]. **Significance** [Ano73g, Gar71, GB72]. **Simple**
[ABA72, Ano74f, Eng75, Gue72, Hoo79, KKM79, MH72, NH72, Rah76, Ron77, SH79, TMB73, Zel72, GH75]. **Simplex** [GK77b, ON75, SN77]. **Simplified** [Box71, EB77a, GH79, MF75b, RS71, Reg76, SP72]. **Simulation**
[Cha70a, GLV74, HK77, J.79m, K.73a, Mer72, Nay72, Sch75, Vin76, Mih75, Mih77]. **Simultaneous**
[Ait74, Bis79, Hah72, Hah75, Has72, HM76b, McK76, Tar76]. **Sines** [Cha70b]. **Single** [Ano72g, Ano74f, Gue71b, HM76a, Lad77, MW78, TMB73, Zac70]. **Single-Stage** [Lad77]. **Singly** [MN77, NS79]. **Singpurwalla** [J.77j]. **Singularities** [MPBD79]. **Situations** [Hin77b, Ste72b]. **Sixth** [Fre73b]. **Size**
[AB71, BS72, BSH71, CHH$^+$71, FD70, Gue74, HG78, J.76g, MF77, NL75, Sch72, Wio70]. **Size-Biased** [Sch72]. **Sizes**
[Ang74, Ano73g, BM78, Fuc78, GB72, Gut73b, SdV73, Ury76]. **Skewness**
[JL79, Rou73]. **Slope** [HP78, OM72]. **Slope-Rotatable** [HP78]. **Small**
[Ano73f, BF74, FR72, GH70, GS71, NS79, Web71]. **Small-Sample** [GH70]. **Smallest** [Aus73, Nád70a]. **Smirnov** [BD73, DM78, LR78, PS77]. **Smith**
[JK71, Smi76]. **Smoothing** [Gro71a, LW71]. **Snedecor** [K.73d]. **Snell**
[Ham75]. **Sobel** [Dud79]. **Social** [Leh71]. **Soforthelfer** [JH73b]. **Solution**
[And73, AF76, Gri72, Hem75, Kal71, Ros75c, Sam78]. **Solutions**
[Haw72, J.79o]. **Some**
[AvdL70, Ano72e, Ano73h, Ano79g, BH70, BD72a, Bis79, Box70b, BD71, BHME73, BF74, CB75, CG76, Cor75, DW73, Dic74, Dol70, Dun78a, Dun71, Dun78c, EB73, EB74, FR72, Gue74, GM79, HB71, HM76b, Hin77a, Hol75, Kow70, Kow71, Krz79, LL78, Low76, Low74, Mal73, MH72, MCL76, Nel75, OB76, Riz71, Rub76, San73, SR75, SS75, TM72, Tuk70, Weg74, YC71]. **Sonquist** [Gle78]. **Sources** [PBT76, Sau73]. **Spaces** [Ano76e, Sne75b]. **spare** [Bha73]. **Spares** [DY70]. **Späth** [Ens76]. **Specific** [Car77b, ML75]. **Specifications** [Car77b]. **Spectra** [WRLI75]. **Spectral**
[Bri73b, SCSB76, Ran70c]. **Spectroscopic** [Mal74, Mar74, BT74].

**Spectrum** [Nea70, Yue78]. **Speizer** [Ens78]. **SPES** [Ano70a]. **Spline** [Lin79, Wol74]. **Sports** [J.77i, J.78e]. **Sprott** [Ano79f]. **SPRT** [Kow71]. **Spuriosity** [Gut73a, GDF78]. **Square** [All71, DeG70, Far75, Low74, McL74a, McL74b, ML75, SR75]. **Squared** [Mie74, Vin76, HK77]. **Squares** [AF76, BD72a, BCK61, GZ79, GWM76, GPS73, Har73b, Hed71, HM77, J.77b, JK71, MT72, MHL77a, RJ78, See73, Wat74, BCK78]. **Srinivasan** [Bri73a]. **Srivastava** [Gri73, J.75a]. **Stage** [ABA72, Ede74, GG70b, Lad77, Sam78, TA75, Wol77b]. **Standard** [BMH76, Joi77]. **Stanley** [Cro78, Gie74, vdV75]. **Starr** [J.78h]. **State** [Ano80c, McD79]. **Statements** [Ano74g]. **Stationarily** [Shu71]. **Stationary** [Weg74]. **Statistic** [Ano73i, Beh72, DW72, HH77, Ken71, Krz79, PS77, PW72, Som70, TW72b, YM74, LR78, Sal75a]. **Statistical** [Ano70a, Ano73a, BKRS78, Bel70, BAB72, Bon76a, Cha70a, CG76, Dol70, Dud79, EB77a, Eva71, Eva72, Fed74b, Fre73c, FH79, Gen77, Gib74, Gol74, Gru73b, Hac78, HN70, Har77, Hei78, Hil74, Hub78, J.75a, J.75f, J.76d, J.76e, J.78l, J.78f, Joh71b, Joh73c, K.71a, K.71c, K.74c, Lan75, LSYF79, McC78b, Mer79, Ram73, Ran70b, Sau73, Sax72, Spr76, Sta70, TJ79, Wat70b, Wil79a, Woo74a, Boa79a, GW75, Add72, Boy74, Con74, Dav77, Fie73, Fre74b, J.78p, J.79q, K.71e, K.73d, Kal75, Kin78, Lac72b, Rus73, Smi77, Ste75, Win71]. **Statisticians** [Sne74, Ano71f, K.74e]. **Statistics** [Ano76f, Ano79g, BH70, BMH76, Boa79a, BF74, Che71, CK75, Cor71, Dav79a, DM78, Fed74a, Fre73b, Fre74a, Gro77, Gue77, Har72, Ing78b, J.75g, J.75h, J.76f, J.76h, J.77d, J.77f, J.77e, J.77l, J.77k, J.77o, J.77q, J.77p, J.78k, J.78o, J.79g, J.79v, J.79f, Joh75, JK74, Jon73, K.74b, Kam72, Kam74, KB75, Kup71, Lan73, Lyn78, MS74, McC72, Mer77, Mil72a, Pap72, Qua74b, Qua74a, Qua75, SR75, Sim76, TM72, Urq73, ZNL79, Zie78, Boa79a, Kin79b, Bha72, Bow77, Bow78, Car77a, Cru78a, Dye74, Ehr77, Eri72, Geo72, Gra72, Gru71a, Hac79, Hal77b, Hei79, Hog74, How77, Ing75, J.75b, J75e, J.76c, J.76a, J.78m, J.78c, J.78a, J.79l, J.79k, J.79o, K.74d, Kin79b, Lac72a, Mye74, Qua71, Qua75, Ros75a, Sch74b, Sen75, Web73, Wei71, Woo74b, Zys70, Add79, Boa79a, Cru78b]. **Statistics** [Dal77, Dyk76, Gle77, J.79r, J.79s, K.73e, Kin79a, Lac71b, Lac74a, Wat73]. **Statistik** [Ens77]. **Statistische** [Bed74, JH73b]. **STD** [Koy78, Koy79, BS79]. **Stein** [Wil79a, DV79, Vin76]. **Stein-Rule** [Wil79a]. **Stein's** [HK77]. **Stellar** [Sau73]. **Stepdown** [Man70b]. **Stephen** [Dra79, Odo77]. **Stepwise** [Goo71, PW72, YC78]. **Steutel** [Luk73]. **Stochastic** [Ano73j, BM74, Gil74, Mar73, TW72a, Fre73c, Hun70]. **Stone** [Gil74, Sax72, Ton72]. **Stopping** [Sim73]. **Storage** [Ven70, K.74a]. **Straight** [For72, WB74]. **Straight-Line** [WB74]. **Strategies** [Bon77, J.77i]. **Stratified** [Gro72, Zac70]. **Stratum** [CHH$^+$71]. **Strength** [CH70, Hal77a]. **Stress** [CH70, Law77b, Man72, MW78, MH77, MH78]. **Stress-Strength** [CH70]. **Stroup** [Boa79a]. **Structural** [Gri79, Kal71]. **Structure** [FW72, Rog70d, Wil70]. **Structures** [K.71d, TC75b]. **Stuart** [Fie73, Gra72]. **Student** [Boa79a, J.78g, CC71, Rel70, YM74]. **studentized**

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**T** [Bow78, Gow72, J.78g, J.79m, K.73d, Lan75, Rog70a, Ron72]. **Table** [GW75, JK71, TC72]. **Tables** [Ano71f, BD78, BK70b, BG78, Gar71, Goo71, Har72, J.75g, J.76h, J.77k, J.78p, J.78o, JD78, Lun75, MF73, MDM77, Sne74, SU79, J.78l, Odo78, J.78q, J.79u]. **Tabular** [Joh73b]. **Tabulated** [Sim79]. **Tailed** [Bry74]. **Tails** [RSO72]. **Tanis** [Hei78]. **Tanur** [J.79k]. **Tapiero** [J.79d]. **Tatsuoka** [Ger75]. **Taylor** [Bow77]. **Teaching** [Boa79a]. **Technique** [CK75, CM71, MW75a, Som70, Whi70]. **Techniques** [Eva71, Eva72, Fed74b, Ger75, Gua71, J.76i, J.79i, K.71c, Lin74, MC73, Rel70, SCSB76, Sne73, For73, J.78n, Mar75]. **Technology** [Dal77, J.79s]. **Technometrics** [BCK78, GH75, HK77, JTS75, Smi76, Kit81, Ton75, FW72]. **Telescoping** [HS71]. **Tell** [Bon77]. **Terms** [DJ77a, DJ77b, GG70a, McL74b]. **Ternary** [CK79]. **Test** [AS73, Ano75e, Bar72, BJN71, BD78, BF74, BS79, CC71, CF76, DW72, DAH73, Fil75, Fuc78, GR72, Har73a, J.77b, KP71, Lun75, Man72, MG74, MF75a, MS74, MW78, MCM75, McD75, MDM77, MH78, Mie74, Nel72a, Ng76, Obe75, Ode71, PK76, PK79, Pre75, Rah76, ST72, Sch71a, SW72, Sta79, Ste78, SI70, TK72, WDFH73, WB75, Wes71, Wil79a, Wol77a, Wol77b, BD73, LH74]. **Testimation** [Rif71]. **Testing** [Ano74f, Ant77, Bai74b, BKRS78, BC79b, Bli72, BK70b, CH73a, Dun74, FP77, GR72, Gre71, Gru73a, HJF78, Igl73, JD78, KA71, Law71, Leo70, MHC77, MS79, NL75, PBT76, Sam78, SLK79, Sha78, Smi77, TMB73, Ziz78].

**Testing-Probability** [Smi77]. **Tests** [Ano73g, BJ75, BS71, Bry74, BH73, Cho73, Cho79, CL70, CL71, DG72, Dan70, DW73, Dub73, EB75, EB77b, FR72, Gar71, GC74, GB72, IR77, Jae76, JB74, Kam74, KKM79, KARR75, Kow70, Kra76, LaB77, Law77b, MD71, McM71, MH77, Moe74, MM73, Nád73, Nai74, NK76, NM78, Obe77, SS75, SS74, Sin71, Sin73, YC78, Bel70]. **Text** [Boa79a]. **th** [For72, Lik74]. **Thanks** [Ano75m]. **Theil** [Fre74b, Han73]. **Their** [BD72b, Bri73a, Cle72b, CG76, HR75, NH72, Par72, Spr78, Zel72]. **Theodore** [Jer70]. **Theoretical** [Gua71, J.79o, Ing75]. **Theory** [Fre73c, Hac79, Hun70, Ing78a, K.73c, Kra76, Lev79, Lut73, Man71c, Nel72b, NH73, NK76, NM78, Odo77, Pre77, Rog70d, Sam73, Sid75, Sim76, Sim73, Smi77, Sta70, Ste75, Zac74, Ben76, Dun77b, Hun74, Kee75, Moe72, Sax72, Sen70, Spr78, Sys75, Tan70, Ton72, Weg76, J.77n]. **Third** [K.74e]. **Thomas** [Mer72]. **Thomasion** [Rog70d]. **Thompson** [Ham75]. **Three** [Ano73f, BLB73, Coh75, Coh76, CN77, DJ77a, Ede74, EB75, GG70b, Hed71, Lem75, Luc78, MF75a, MBC79, McL74b, MB78a, MB78b, SP77, Sor72b, Web71, Jac80]. **Three-Level** [Ano73f, Luc78, MB78a, MB78b, Web71]. **Three-Parameter** [CN77, EB75]. **Three-Stage** [Ede74]. **Threshold** [MF75a]. **Thumb** [AB71]. **Tiao** [Hil74]. **Time** [AvdL70, AB74, CB75, CF76, Cle71, Cle72a, Cle72b, CM71, Dav79b, Dun77a, Gru71b, HD70, J.76f, J.79e, LR76, McC78b, MH72, Nel74, Par72, Pre77, Rif71, Sar71, Wan71, Kle77, Weg76]. **Time-to-Fail** [Gru71b]. **Times** [AJ77, Bag70, DY70, HT74, Kam77, Man72, Nád73, PK76, SS74, Bha73, J.78q]. **Tinker** [Ens78]. **Title** [K.71a]. **Titles** [J.77f, J.77q]. **Toeplitz** [Ray70]. **Tolerance** [Dun78c, EB78c, Fau70, FD70, Fra77, FKRO71, Law75a, MF73, MF77, RSO72, TBA70, TJ79, GPU76]. **Tolerances** [JR72]. **Tolerancing** [Eva71, Eva72]. **Tong** [JTS75]. **Tool** [BG78, Fed75]. **Tools** [Fed74b]. **Total** [CHH$^+$71]. **Toutenburg** [Boa79b]. **Tracking** [Pas79]. **Tracy** [K.74d]. **Trade** [Kee75, Kno71]. **Traffic** [Ano73j, Ano80c, Mar73, McD79]. **Training** [Wat70b]. **Trajectory** [Bus71]. **Transform** [Ano84, HL76, IC79]. **Transformation** [BH74, Cha79, GH79, HH73, Tho75, WY78]. **Transformations** [BWL78, Kow70, Sen74, TK72]. **Transformed** [Fuc78]. **Transient** [BGH73]. **Transients** [Bri73b]. **Transition** [WB74]. **Treatment** [Fed75, SOE75]. **Treatments** [BH77, SdV73, BN72]. **Tree** [J.77j]. **Trending** [LR76]. **Trials** [Gre70b, Sap73, Fle76]. **Triangles** [CK79]. **Trimmed** [MHL77a, MHL77b]. **Triple** [Pat76b]. **Trirogoff** [Bis72b]. **trivariate** [TC72]. **Truncated** [AS73, Coh72, DM78, Gro71b, Gue71a, Ham72a, KKM79, KB75, SI70]. **Truncation** [Man75]. **Truth** [Bon76b, Bon77]. **Tsokos** [J.77n, Zac74]. **Tucker** [Har70]. **Tukey** [J.77d, J.77f, J.77e, J.77o, J.77q, J.77p, Law75b, Qua74b, Qua74a, Wes71]. **Tuma** [K.71b]. **Turner** [vdV75]. **Turoff** [J.76i]. **Two** [Ano73f, AJ77, BE73, BL71, BC79b, Beh70, BH77, BG78, Cha79, CH73a, Cho79, Dan78, DM77, DL70, DAH73, Dun78c, EB74, EB75, EB78c, EB79, GW75, Gri70, Gru71c, Hah77, HW75, Har73a, HJ76, Jae70, Jae76, Joh70c,

Joh70b, JD78, Kam74, KB75, KP71, Law77a, Leo70, LO79, Lik74, Low76, Man72, MF75a, MDM77, McK76, MD71, McM71, MPB70, MM73, MA78, Nea70, Pie73, Ray72, Sal75b, Sam78, SG71, SS76, SdV73, TW72b, Tho73, TA75, Var70, WB74, Web71, WDFH73, Wol77b, AB71, GPU76, And75]. **Two-** [Ano73f, Web71]. **Two-Parameter** [BE73, EB74, EB75, EB78c, Lik74, Man72, TW72b, GPU76]. **Two-Phase** [BC79b]. **Two-Point** [And75]. **Two-Regime** [WB74]. **Two-Sample** [Cho79, EB79, Wol77b]. **Two-Sided** [LO79, SdV73]. **Two-Stage** [Sam78, TA75, Wol77b]. **Two-Way** [BG78, Dan78, GW75, HW75, HJ76, JD78, Low76, MA78]. **Tyn** [Cha75a]. **Type** [Ano79g, Bry71, Gue74, MC72, Sha79, Sha78, Sin73, TM72, DW72, Har71, TW72b]. **Type-I** [DW72]. **Types** [Luc76, McL74b].

**U** [Cha75a]. **Udny** [Fie73]. **Unbalanced** [Hin77b, See70]. **Unbiased** [BR73, EB77b, EB78a, MF77, NH73, SG71, Sch76, SS78, WK77]. **Unconditional** [MDM77]. **Underlying** [Law73]. **Unequal** [BD78, Bis79, Leo75, vN79]. **Uniform** [McD76, TC73, TS79, TC72]. **Uniformity** [Ng76]. **Uniformly** [EB77b]. **Unit** [MW78]. **Units** [Har74]. **Univariate** [Che71, Gut73a, Sor73, GDF78]. **Unknown** [DAH73, Har73a, McM71, MM73, OB76, Tak72]. **Unknown-Sigma** [Tak72]. **Unmodeled** [Bus71]. **Unweighted** [Cor77]. **Update** [Cor79]. **upon** [Ano72g, Gue71b]. **Upper** [KARR75]. **Upton** [Sim79]. **Uranium** [CBI79]. **Urn** [Spr78]. **Use** [Ano71f, Ano84, Bai74a, BH78, BMH76, CO75, Hub78, IC79, Kin79b, Kit79, LM72, NGM70, Nea70, PW72, Sne71, Sne75a, Woo73, Kit81]. **Used** [Hoc72, JH73a, Leo70]. **Useful** [BK70b, Krz79, Whi70]. **Uses** [RTDM79]. **Using** [ABA72, AA74, Aus73, Bod70, BCK61, BR75, Cor77, Gre71, Har74, HH73, JB76, Kam72, KN74, Mar75, NW79, Pat76a, Rah76, Sin73, SLM74, TS79, WB74, Wig76, Zei73, BCK78, McC78a].

**V** [Bel70, Bis72b, Hac79, Hei78, Ing75, J.76b, J.79o, J.79u, Luc73, Sac75, Sen75, Spr79, Wat73]. **V.** [HH73]. **Validation** [GHW79, Sne77]. **Validatory** [Wol78]. **Validity** [Whe75]. **Value** [And75, Bai72, Bai73, Eas78, EB73, EB74, Eng75, EB77a, Has72, Law75a, Law78, MF73, MF77, NM78, TW72b]. **Values** [BK70b, BDH70, Dun71, Har74, HG73, JH79, Joh73b, MBC79, Pre71, Rub76, Sin72, You72a, Zah75b]. **Variable** [Ait74, All74, Bea70, BMP77, Hun74, Kus79, Man70b, Man71d, McC75a, McK79]. **Variables** [All71, BL71, BK70b, Cas76, Cha72, Fuc78, HH77, Har79, Hel74, LH70, MBC79, NW79, OlHS77, Sch70, SB72b, Tho73, Whe70, WY78, LH77]. **Variance** [BD72b, Bin74b, BD78, Bis79, BH74, BR73, CS76, CK79, Dav79b, GG70b, GH79, GS71, Hal79, Hel74, HL76, JS76, Krz79, Low76, Man71a, MD71, McM71, MM73, MA78, Nai74, Rel70, Sal75b, Sch76, See70, SW72, Sne76, SS78, TA71, WC70, WB75, Whe70, Wio70, WK77]. **Variances** [BD78, Bis79, Cha70b, Cor77, GG70a, HW75, Leo75, Low70, MN77, TJ79].

**Variate** [McD76]. **Variates** [AR73]. **Variation** [AR73, Ber72b, IM70, Zei73]. **Variational** [FM71]. **Varieties** [Joh78, Joh73a]. **Vasant** [Ing78b]. **Vasudevan** [Bri73a]. **Vaughn** [Woo75]. **Vector** [Nád70a]. **Vectors** [JH73a]. **Verification** [Lev79]. **Version** [Wes71]. **versus** [CM71, Cor77]. **Vertices** [SM74]. **Via** [Mar76, Bin74a]. **Vick** [Bon76a]. **Viewed** [WB71]. **Viewpoint** [WG78]. **Vincze** [J75e]. **Vinod** [HK77]. **Virginia** [Hei76]. **Visual** [San72, San73]. **Vital** [Car77a]. **Vocabulary** [Dil71]. **Vol** [J.75g, J.76h, J.78o]. **Volume** [Ano70o, Ano71l, Ano72l, Ano73p, Ano74l, Ano75l, Ano76o, Ano77q, Ano78o, Ano78p, Ano79p, Bor72, Cra74, Fre73b, Har72, J.77k, J.79q, J.79g, J.79f, K.71d, K.73b, K.73a, Lac71b, Sne74]. **VOQL** [Hal79]. **Vote** [Ano75m]. **vs** [LW71, MF75a, Scl72].

**W** [Add72, Add79, Ano74e, Bha72, Boy74, Dav70, Fre73a, Fre73c, Gle77, GH75, Hay73, Hea78, Hel71a, Hub78, J.76d, J.76e, J.76a, J.77d, J.77f, J.77e, J.77o, J.77q, J.77p, J.78n, J.78l, K.73d, Lac71b, Lac74a, Lan75, Law75b, Leh71, Luk73, Mil72a, O'F73, Odo77, Qua74b, Qua74a, Sne76, Spr72]. **Waiting** [CM71, HD70]. **Waiting-Time** [HD70]. **Wald** [Sha79]. **Walpole** [Fed74a, Dye74, Har77]. **Wani** [Gol74]. **Wasan** [Rog70a]. **Water** [K.74a, Ven70]. **Watts** [Ano75f, Ran70c]. **Way** [BG78, Dan78, GW75, HW75, HJ76, JD78, Kus79, Low76, MA78, Nai74]. **Wayne** [McC78b]. **Weak** [Ber72b]. **Weather** [Dav79a, Mie74, SOE75]. **Weibull** [Ano73k, Ant77, Eas78, AJ77, Bai72, Bai73, BL74b, BAB72, Coh65, Coh73, Coh75, D'A71a, D'A71b, Dan70, DA73, EB73, EB74, Eng75, EB75, EB77a, EB78b, EB79, Fal70, Fin76, Gro71b, HBA71, KARR75, Law73, Law75a, Law78, LL78, Lem75, Man70a, Man71b, Man72, MF73, MF75a, MF75b, MF77, MHC77, MN77, NM78, Rou73, SS76, SA79, SW75, TBA70, TW72b]. **Weighing** [Cam77]. **Weight** [Bin74b]. **Weighted** [Cor77, Har73b, Hin77a, JK71, NW79, Ste70, WC70]. **Weighting** [BH74]. **Weights** [GZ79]. **Weischedel** [Gor76]. **Welch** [Ros75c]. **Wetherill** [Boa79a, Ehr77, Tsi78]. **Wheeler** [J.76b]. **Where** [Sar71]. **Whether** [Leo70]. **Which** [Bri73b, BF74, Cha70b, DY70, Gru71b, Hoc72, Luc76, RSO72, Sta79, Ste72b]. **White** [Ano80b]. **Whitehouse** [Mar75]. **Whittemore** [J.79h]. **Wide** [Tak72]. **Wilf** [J.79q]. **Wilkinson** [J.79m]. **Wilks** [Gra72]. **Willems** [Bak74]. **William** [Gle78, J.79k, Mil72a, Sal75a, Sam73, Woo74a]. **Williams** [Dil71, J.77l, J.79a]. **Windowing** [Yue78]. **Winkler** [Hol73, Lac71b]. **Winn** [Kin79b]. **Winsorized** [MHL77a, YF76]. **Wiorkowski** [Cro71]. **Within** [BR79, J.76e, Sap73]. **Within-Group** [BR79]. **Within-Groups** [J.76e]. **without** [Gre71]. **Wolfe** [Ano78e, Gib74]. **Wolfowitz** [Sha79]. **Wolock** [Ano74e]. **Wonnacott** [Bow78, Bow78]. **Wood** [Sne72a]. **Work** [Buc73]. **Working** [Ens78]. **works** [CGO07]. **World** [Boa79a].

**X** [Sau73, Ury72]. **X-Ray** [Sau73].

**Yates** [Ber72a]. **Year** [Ens78, Ven70]. **Yonathan** [Cha75b]. **Youden** [DeG70]. **Yu** [Sen75]. **Yule** [Fie73, Fie73]. **Yvonne** [Odo77].

**Z** [J.78l]. **Zeleny** [J.78h]. **Zellner** [Goo76, Goo75, J.75h]. **Zemroch** [J.79u]. **Zero** [Nád73, PK76, SS74]. **Ziegler** [J.76a]. **Zionts** [Lin75].

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